

## PCTEST

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# **HEARING AID COMPATIBILITY**

#### Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

Date of Testing: 10/4/2021 - 10/18/2021 **Test Site/Location:** PCTEST, Columbia, MD, USA **Test Report Serial No.:** 1M2109090103-21-R3.A3L Date of Issue: 11/13/2021

## FCC ID:

## A3LSMS906U

**APPLICANT:** 

## SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: Application Type: FCC Rule Part(s): **HAC Standard:** 

DUT Type: Model: Additional Model(s): **Test Device Serial No.:**  **RF Emissions Testing** Certification CFR §20.19(b) ANSI C63.19-2011 285076 D01 HAC Guidance v05 285076 D02 T-Coil testing for CMRS IP v03 **Portable Handset** SM-S906U SM-S906U1 Pre-Production Sample [S/N: 0271M]

## C63.19-2011 HAC Category:

## M3 (RF EMISSIONS CATEGORY)

Note: This revised Test Report (S/N: 1M2109090103-21-R3.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President



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## 1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658<sup>1</sup> to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide suffer from hearing loss.

## Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid *in-vitu* 

### <sup>1</sup> FCC Rule & Order, WT Docket 01-309 RM-8658

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## 2. DUT DESCRIPTION



FCC ID:	A3LSMS906U
Manufacturer:	Samsung Electronics Co., Ltd.
	129, Samsung-ro, Maetan dong,
	Yeongtong-gu, Suwon-si
	Gyeonggi-do 16677, Korea
Model:	SM-S906U
Additional Model(s):	SM-S906U1
Serial Number:	0271M
Antenna Configurations:	Internal Antenna
DUT Type:	Portable Handset

#### I. Power Reduction for WIFI

This device uses an independent fixed level power reduction mechanism for all WIFI operations during voice or VoIP held to ear scenarios. Reduced powers were used to evaluate for low-power exemption in Section 9.II for WIFI. Detailed descriptions of the power reduction mechanism are included in the operational description.

#### II. LTE Band Selection

This device supports LTE capabilities with overlapping transmission frequency ranges. When the supported frequency range of an LTE band falls completely within an LTE band with a larger transmission frequency range, both LTE bands have the same target power (or the band with the larger transmission frequency range has a higher target power), and both LTE bands share the same transmission path and signal characteristics, hearing-aid compatibility compliance was only assessed for the band with the larger transmission frequency range. However, overlapped LTE bands which are anchor bands for dual connectivity (EN-DC) scenarios between LTE and NR were evaluated as independent LTE bands.

#### III. NR Band Selection

This device supports NR capabilities with overlapping transmission frequency ranges. When the supported frequency range of an NR band falls completely within an NR band with a larger transmission frequency range, both NR bands have the same target power (or the band with the larger transmission frequency range has a higher target power), and both NR bands share the same transmission path and signal characteristics, hearing-aid compatibility compliance was only assessed for the band with the larger transmission frequency range.

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		A3LSMS9060 HAC AIr Interfaces						
Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service			
GSM	850 1900	VO	Yes	Yes: WIFI or BT	CMRS Voice			
	GPRS/EDGE	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo			
	850							
UMTS	1700	VD	No <sup>1</sup>	Yes: WIFI or BT	CMRS Voice			
	1900							
	HSPA	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo			
	680 (B71) 700 (B12)		No <sup>1 2</sup>					
	780 (B12)							
	790 (B14)							
	850 (B5)							
	850 (B26)	10						
LTE (FDD)	1700 (B4)	VD	No <sup>1</sup>	Yes: NR, WIFI or BT	VoLTE, Google Duo			
	1700 (B66)							
	1900 (B2)							
	1900 (B25)							
	2300 (B30)							
	2500 (B7)							
	2600 (B38)	10		V NO 11/151 OT				
LTE (TDD)	2600 (B41)	VD	Yes	Yes: NR, WIFI or BT	VoLTE, Google Duo			
	3600 (B48)		No <sup>1 2</sup>					
	680 (n71) 700 (n12)		NO <sup>+ -</sup>					
	850 (n5)	VD	No¹	Yes: LTE, WIFI or BT				
	1700 (n66)				VoNR, Google Duo			
NR (FDD)	1900 (n2)							
	1900 (n25)							
	2300 (n30)							
	2500 (n7)							
	2600 (n38)							
	2600 (n41)		Yes		VoNR, Google Duo			
	3500 (n77, DoD)				,			
NR (TDD)	3700 (n77)	VD		Yes: LTE, WIFI or BT				
	24500 (n258)							
	28000 (n261)		No <sup>3</sup>		Google Duo			
	39000 (n260) 2450							
	5200 (U-NII 1)							
	5300 (U-NII 2A)							
	5500 (U-NII 2C)		No <sup>1</sup>					
14/151	5800 (U-NII 3)	VD		Voc CCM UNITS ITS ND				
WIFI	5900 (U-NII 4)	VD		Yes: GSM, UMTS, LTE, or NR	VoWIFI, Google Duo			
	6175 (U-NII 5)							
	6475 (U-NII 6)		No <sup>4</sup>					
	6700 (U-NII 7)		NO					
	7000 (U-NII 8)	-						
BT Type Transport	2450	DT	No Notes:	Yes: GSM, UMTS, LTE, or NR	N/A			
We hanspure       Notes:         (0) = Voice Only       1. Evaluated for MIF and low-power exemption.         (1) = Digital Data - Not intended for Voice Services       2. LTE B71 and NR n71, while outside the scope of ANSI C63.19 and FCC HAC regulations, were additionally tested according to the existing HAC procedures with currently available test equipment.         (2) = CMRS and/or IP Voice over Data Transport       3. n559, n260, and n261 are currently outside the scope of ANSI C63.19 and FCC HAC regulations therefore they were not evaluated.         (4) WIFI U-NII bands 5 through 8 were not evalued due to equipment limitations and being outside of the current scope of ANSI C63.19 and FCC HAC regulations.								

#### Table 2-1 A3LSMS906U HAC Air Interfaces

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#### ANSI/IEEE C63.19 PERFORMANCE CATEGORIES 3.

#### I. **RF EMISSIONS**

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters				
Near field Category	E-field emissions CW dB(V/m)				
	f < 960 MHz				
M1	50 to 55				
M2	45 to 50				
M3	40 to 45				
M4	< 40				
	f > 960 MHz				
M1	40 to 45				
M2	35 to 40				
M3	30 to 35				
M4	< 30				
Table 3-1WD near-field categories as defined in ANSI C63.19-2011					

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# 4. SYSTEM SPECIFICATIONS

#### EF3DV3 E-Field Probe Description

Construction:	One dipole parallel, two dipoles normal to probe axis Built-in shielding against static charges
Calibration:	In air from 30 MHz to 6.0 GHz (absolute accuracy ±5.1%, k=2)
Frequency:	30  MHz to  > 6  GHz;
	Linearity: ± 0.2 dB (30 MHz to 6 GHz)
Directivity	± 0.2 dB in air (rotation around probe axis)
-	± 0.4 dB in air (rotation normal to probe axis)
Dynamic Range	2 V/m to > 1000 V/m
, ,	(M3 or better device readings fall well below diode
	compression point)
Linearity:	± 0.2 dB
Dimensions	Overall length: 337 mm (Tip: 20 mm)
	Tip diameter: 4.0 mm (Body: 12 mm)
	Distance from probe tip to dipole centers: 1.5 mm

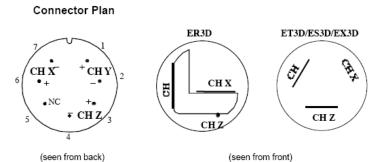


**Figure 4-1** E-field Free-space Probe

#### **Probe Tip Description**

HAC field measurements take place in the close near field with high gradients. Increasing the measuring distance from the source will generally decrease the measured field values (in case of the validation dipole approx. 10% per mm).

The electric field probes have an irregular internal geometry because it is physically not possible to have the 3 orthogonal sensors situated with the same center. The effect of the different sensor centers is accounted for in the HAC uncertainty budget ("sensor displacement").



The antistatic shielding inside the probe is connected to the probe connector case.

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## Instrumentation Chain

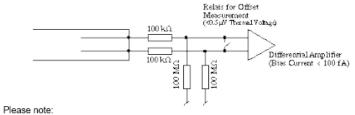
## Equation 1 Conversion of Connector Voltage $u_i$ to E-Field $E_i$

$$E_i = \sqrt{\frac{u_i + (u_i^2 \cdot CF)/(DCP)}{Norm_i \cdot ConvF}}$$

whereby

Eı:	electric field in V/m
Uj.	voltage of channel i at the connector in μV
Norm <sub>i</sub> :	sensitivity of channel i in µV/(V/m) <sup>2</sup>
ConvF:	enhancement factor in liquid (ConvF=1 for Air)
DCP:	diode compression point in µV
CF:	signal crest factor (peak power/average power)

#### **Conditions of Calibration**



a lower input impedance of the amplifier will result in different sensitivity factors Norm, and DCP

larger bias currents will cause higher offset

#### **Probe Response to Frequency**

The E-field sensors have inherently a very flat frequency response. They are calibrated with a number of frequencies resulting in a common calibration factor, with the frequency behavior documented in the calibration certificate (See also below).

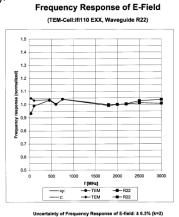


Figure 4-2 E-Field Probe Frequency Response

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#### **SPEAG Robotic System**

E-field measurements are performed using the DASY5 automated dosimetric assessment system. The DASY5 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich. Switzerland and consists of high precision robotics system (Staubli), robot controller, Intel CORE i7 computer, near-field probe, probe alignment sensor, and the HAC phantom. The robot is a six-axis industrial robot performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).



Figure 4-3 SPEAG Robotic System

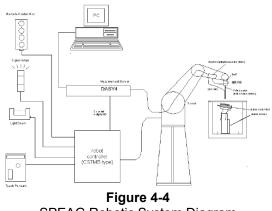
#### System Hardware

A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and a remote control used to drive the robot motors. The PC consists of the computer with operating system and RF Measurement Software DASY5 v52.8 (with HAC Extension), A/D interface card, monitor, mouse, and keyboard. The Staubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit that performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

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#### System Electronics

The DAE consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.



SPEAG Robotic System Diagram

#### **DASY5** Instrumentation Chain

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power. The formula for each channel can be given as:

$$V_i = U_i + U_i^2 \cdot \frac{cf}{dcp_i}$$

with	$V_i$	= compensated signal of channel i	(i = x, y, z)
	$U_i$	= input signal of channel i	(i = x, y, z)
	cf	= crest factor of exciting field	(DASY parameter)
	$dcp_i$	= diode compression point	(DASY parameter)

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From the compensated input signals the primary field data for each channel can be evaluated:

E – fieldprobes : 
$$E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

with 
$$V_i$$
 = compensated signal of channel i (i = x, y, z)  
 $Norm_i$  = sensor sensitivity of channel i (i = x, y, z)  
 $\mu V/(V/m)^2$  for E-field Probes  
 $ConvF$  = sensitivity enhancement in solution  
 $E_i$  = electric field strength of channel i in V/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

The measurement/integration time per point, as specified by the system manufacturer is >500ms.

The signal response time is evaluated as the time required by the system to reach 90% of the expected final value after an on/off switch of the power source with an integration time of 500ms and a probe response time of <5 ms. In the current implementation, DASY5 waits longer than 100ms after having reached the grid point before starting a measurement, i.e., the response time uncertainty is negligible.

If the device under test does not emit a CW signal, the integration time applied to measure the electric field at a specific point may introduce additional uncertainties due to the discretization. The tolerances for the different systems had the worst-case of 2.6%.

#### **Environmental Conditions**

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

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# 5. TEST PROCEDURE

## I. RF EMISSIONS

# **Test Instructions**

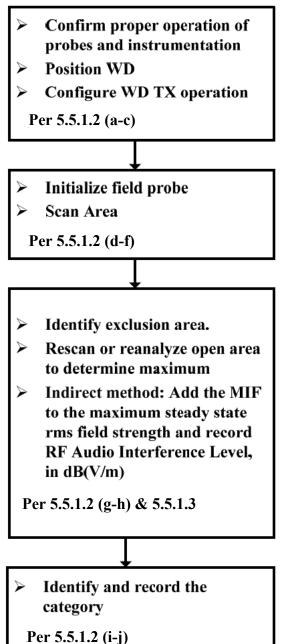
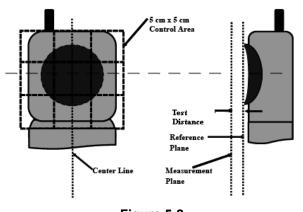
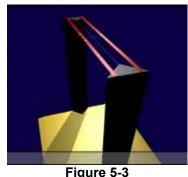


Figure 5-1 RF Emissions Flow Chart

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#### **Test Setup**





**HAC Phantom** 

#### Figure 5-2 E-Field Emissions Test Setup Diagram (See Test Photographs for actual WD scan grid overlay)

#### **RF Emissions Test Procedure:**

The following illustrate a typical RF emissions test scan over a wireless communications device:

- 1. Proper operation of the field probe, probe measurement system, other instrumentation, and the positioning system was confirmed.
- 2. WD is positioned in its intended test position, acoustic output point of the device perpendicular to the field probe.
- 3. The WD operation for maximum rated RF output power was configured and confirmed with the base station simulator, at the test channel and other normal operating parameters as intended for the test. The battery was ensured to be fully charged before each test.
- 4. The center sub-grid was centered over the center of the acoustic output (also audio band magnetic output, if applicable). The WD audio output was positioned tangent (as physically possible) to the measurement plane.
- 5. A surface calibration was performed before each setup change to ensure repeatable spacing and proper maintenance of the measurement plane using the HAC Phantom.
- 6. The measurement system measured the field strength at the reference location.
- 7. Measurements at 2mm or 5mm increments in the 5 x 5 cm region were performed at a distance 15 mm from the center point of the probe measurement element to the WD. Of the 9 subgrids (see Figure 5-2), 3 contiguous subgrids may be excluded from the measurement in order to account for localized areas of higher field intensities. The center subgrid containing the acoustic output or audio band magnetic output may not excluded. A 360° rotation about the azimuth axis at the maximum interpolated position was measured. For the worst-case condition, the peak reading from this rotation was used in re-evaluating the HAC category.
- 8. The system performed a drift evaluation by measuring the field at the reference location. If the power drift deviated by more than 5%, the HAC test and drift measurements were repeated.

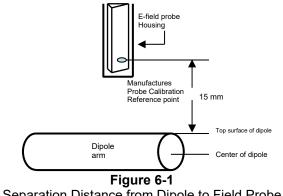
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#### 6. SYSTEM CHECK

#### I. System Check Parameters

The input signal was an un-modulated continuous wave. The following points were taken into consideration in performing this check:

- Average Input Power P = 100mW RMS (20dBm RMS) after adjustment for return loss
- The test fixture must meet the 2 wavelength separation criterion
- The proper measurement of the 15 mm probe to dipole separation, which is measured from top surface of the dipole to the calibration reference point of the sensor, defined by the probe manufacturer is shown in the following diagram:



Separation Distance from Dipole to Field Probe

RF power was recorded using both an average reading meter and a peak reading meter. Readings of the probe are provided by the measurement system.

To assure proper operation of the near-field measurement probe the input power to the dipole shall be commensurate with the full rated output power of the wireless device [e.g. - for a cellular phone wireless device the average peak antenna input power will be on the order of 100mW (20dBm) RMS] after adjustment for any mismatch.

#### II. Validation Procedure

A dipole antenna meeting the requirements given in C63.19 was placed in the position normally occupied by the WD.

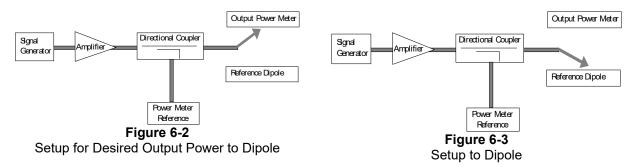
The length of the dipole was scanned, and the average peak value was recorded.

#### Measurement of CW

Using the near-field measurement system, scan the antenna over the radiating dipole and record the greatest field reading observed. Due to the nature of E-fields about free-space dipoles, the two E-field peaks measured over the dipole are averaged to compensate for non-parallelity of the setup (see manufacturer method on dipole calibration certificates, page 2). Field strength measurements shall be made only when the probe is stationary.

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RF power was recorded using both an average and a peak power reading meter.



Using this setup configuration, the signal generator was adjusted for the desired output power (100mW) at a specified frequency. The reference power from the coupled port of the directional coupler is recorded. Next, the output cable is connected to the reference dipole, as shown in Figure 6-3.

The input signal level was adjusted until the reference power from the coupled port of the directional coupler was the same as previously recorded, to compensate for the impedance mismatch between the output cable and the reference dipole. To assure proper operation of the near-field measurement probe the input power to the reference dipole was verified to the full rated output power of the wireless device. The dipole was secured in a holder in a manner to meet the 20 dB reflection. The near-field measurement probe was positioned over the dipole. The antenna was scanned over the appropriate sized area to cover the dipole from end to end. SPEAG uses 2D interpolation algorithms between the measured points. Please see below two dimensional plots showing that the interpolated values interpolate smoothly between 5mm steps for a free-space RF dipole:



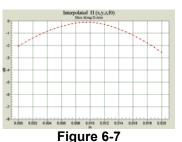
2-D Raw Data from scan along dipole axis



2-D Raw Data from scan along transverse axis



2-D Interpolated points from scan along dipole axis



2-D Interpolated points from scan along transverse axis

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#### III. System Check Results

Date	Frequency (MHz)	Probe S/N	DAE S/N	Dipole S/N	Input Power (dBm)	E-field Result (V/m)	Target Field (V/m)	% Deviation
10/4/2021	835			1003	20.0	109.1	108.4	0.6%
10/4/2021	1880			1137	20.0	88.3	87.9	0.4%
10/11/2021	2600			1012	20.0	87.9	86.5	1.6%
10/18/2021	2600	4035	1530	1012	20.0	86.0	86.5	-0.6%
10/11/2021	3500			1005	20.0	86.3	84.4	2.2%
10/18/2021	3500			1015	20.0	85.8	82.8	3.6%
10/18/2021	3900			1015	20.0	79.7	80.9	-1.5%

Table 6-1 \_\_\_\_

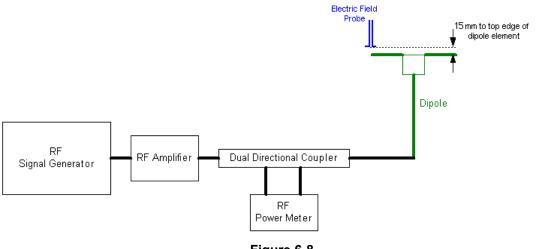


Figure 6-8 System Check Setup

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# 7. MODULATION INTERFERENCE FACTOR

## I. Measuring Modulation Interference Factors

For any specific fixed and repeatable modulated signal, a modulation interference factor (MIF, expressed in dB) may be determined that relates its interference potential to its steady-state RMS signal level or average power level. This factor is a function only of the audio-frequency amplitude modulation characteristics of the signal and is the same for field-strength and conducted power measurements. The MIF is valid only for a specific repeatable audio-frequency amplitude modulation characteristic; any change in modulation characteristic requires determination and application of a new MIF.

The MIF may be determined using a radiated RF field or a conducted RF signal:

- a. Using RF illumination or conducted coupling, apply the specific modulated signal in question to the measurement system at a level within its confirmed operating dynamic range.
- b. Measure the steady-state RMS level at the output of the fast probe or sensor.
- c. Measure the steady-state average level at the weighting output.
- d. Without changing the square-law detector or weighting system, and using RF illumination or conducted coupling, substitute for the specific modulated signal a 1 kHz, 80% amplitude modulated carrier at the same frequency and adjust its strength until the level at the weighting output equals the step c) measurement.
- e. Without changing the carrier level from step d), remove the 1 kHz modulation and again measure the steady-state RMS level indicated at the output of the fast probe or sensor.
- f. The MIF for the specific modulation characteristic is provided by the ratio of the step e) measurement to the step b) measurement, expressed in dB (20 × log[(step e)/(step b)]).

The following procedure was used to measure the MIF using the SPEAG Audio Interference Analyzer (AIA), Type No: SE UMS 170 CB, Serial No.: 1010:

- 1. The device was placed into a simulated call using a base station simulator or set to transmit using test software for a given mode.
- 2. The device was then set to continuously transmit at maximum power.
- 3. Using a coupler if needed, the device output signal was connected to the RF In port of the AIA, which was connected to a desktop computer. Alternatively, a radiated RF signal may be used with the AIA's built-in antenna.
- 4. The MIF measurement procedure in the DASY software was run, and the resulting MIF value was recorded.
- 5. Steps 1-4 were repeated for all CMRS air interfaces, frequency bands, and modulations.

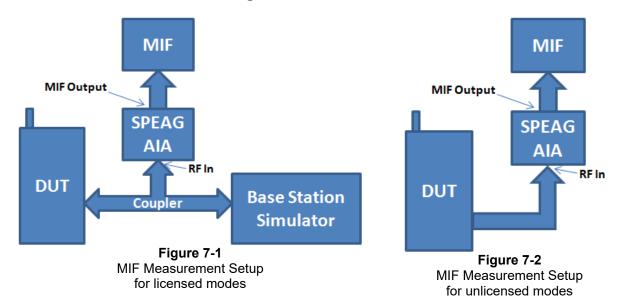
The modulation interference factors obtained were applied to readings taken of the actual wireless device in order to obtain an accurate audio interference level reading using the formula:

## Audio Interference Level [dB(V/m)] = 20 \* log[Raw Field Value (V/m)] + MIF (dB)

Because the MIF value is output power independent, MIF values for a given mode should be constant across all devices; however, per C63.19-2011 §D.7, MIF values should be measured for each device being evaluated. The applicable modes for this device have been investigated in this section of the report.

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## II. MIF Measurement Block Diagrams



## III. Measured Modulation Interference Factors:

Table 7-1           GSM Modulation Interference Factors <sup>1</sup>											
Ma	ode		GSM1900								
IVIC	bae	128	190	251	512 661 8						
0014	Voice	3.58	3.58	3.58	3.57	3.58	3.58				
GSM	EDGE	3.79	3.82	3.81	3.68	3.69	3.76				

 Table 7-2

 UMTS Modulation Interference Factors<sup>1</sup>

M	ode		UMTS V			UMTS IV			UMTS II 9400 9538 -24.12 -24.44 -24.43 -24.64		
IVIC	bue	4132	4183	4233	1312	1412	1513	9262	9400	9538	
UMTS	12.2 kbps RMC	-23.79	-23.83	-24.29	-24.66	-24.46	-24.15	-24.13	-24.12	-24.44	
	12.2 kbps AMR	-24.68	-24.04	-25.23	-24.42	-24.41	-24.41	-24.43	-24.43	-24.64	
	HSUPA Subtest1	-22.21	-23.74	-23.70	-23.28	-23.63	-22.63	-21.08	-23.66	-23.45	

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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			ouulation	Interiorent			
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
71	680.5	133297	20	16QAM	1	0	-9.87
12	707.5	23095	10	16QAM	1	0	-9.83
13	782.0	23230	10	16QAM	1	0	-9.97
14	793.0	23330	10	16QAM	1	0	-9.84
26	831.5	26865	15	16QAM	1	0	-9.73
5	836.5	20525	10	16QAM	1	0	-10.05
66	1745.0	132322	20	16QAM	1	0	-10.01
2	1880.0	18900	20	16QAM	1	0	-9.76
25	1882.5	26365	20	16QAM	1	0	-9.85
30	2310.0	27710	10	16QAM	1	0	-9.80
7	2535.0	21100	20	16QAM	1	0	-9.74
26	831.5	26865	15	QPSK	1	0	-14.04
26	831.5	26865	15	64QAM	1	0	-9.44
26	831.5	26865	15	256QAM	1	0	-9.29
26	831.5	26865	15	256QAM	1	36	-9.43
26	831.5	26865	15	256QAM	1	74	-9.32
26	831.5	26865	15	256QAM	36	0	-15.98
26	831.5	26865	15	256QAM	75	0	-16.72
26	831.5	26865	10	256QAM	1	0	-9.37
26	831.5	26865	5	256QAM	1	0	-9.42
26	831.5	26865	3	256QAM	1	0	-9.41
26	831.5	26865	1.4	256QAM	1	0	-9.43
26	821.5	26765	15	256QAM	1	0	-9.39
26	841.5	26965	15	256QAM	1	0	-9.39

 Table 7-3

 LTE FDD Modulation Interference Factors<sup>1,2</sup>

LTE FDD Uplink Carrier Aggregation Modulation Interference Factor<sup>1,3</sup>

				PCC							SCC				
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (UL) Channel	PCC (UL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	SCC (UL) Channel	SCC (UL) Frequency [MHz]	Modulation	SCC UL# RB	SCC UL RB Offset	MIF (dB)
CA_5B	LTE B5	10	20525	836.5	16QAM	1	0	LTE B5	5	20453	829.3	16QAM	1	24	-10.10
CA_66B	LTE B66	10	132322	1745.0	16QAM	1	0	LTE B66	10	132223	1735.1	16QAM	1	49	-9.76
CA_66C	LTE B66	20	132322	1745.0	16QAM	1	0	LTE B66	20	132124	1725.2	16QAM	1	99	-9.74

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup> Note: All FDD LTE bands were found to have substantially similar MIF values given similar RB, BW, and modulation configurations.

<sup>3</sup> Note: LTE FDD ULCA was evaluated to ensure LTE FDD standalone was the worst-case scenario. The configurations in Table 7-4 were determined from Table 7-3 and satisfy the configuration requirements as defined in 3GPP 36.101.

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L	LTE TOD D41 Fower Class 5 Wouldation Interference Factors											
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]					
41	2593.0	40620	20	QPSK	1	0	3.63					
41	2593.0	40620	20	16QAM	1	0	3.74					
41	2593.0	40620	20	64QAM	1	0	3.58					
41	2593.0	40620	20	256QAM	1	0	3.38					
41	2593.0	40620	20	16QAM	1	50	3.88					
41	2593.0	40620	20	16QAM	1	99	3.71					
41	2593.0	40620	20	16QAM	50	0	3.45					
41	2593.0	40620	20	16QAM	100	0	3.46					
41	2593.0	40620	15	16QAM	1	36	3.76					
41	2593.0	40620	10	16QAM	1	25	3.70					
41	2593.0	40620	5	16QAM	1	12	3.69					
41	2506.0	39750	20	16QAM	1	50	3.79					
41	2549.5	40185	20	16QAM	1	50	3.78					
41	2636.5	41055	20	16QAM	1	50	3.78					
41	2680.0	41490	20	16QAM	1	50	3.82					

 Table 7-5

 LTE TDD B41 Power Class 3 Modulation Interference Factors<sup>1,2</sup>

 Table 7-6

 LTE TDD B41 Power Class 2 Modulation Interference Factors<sup>1,2</sup>

			-			1         0           1         0           1         0           1         0           1         0           1         0		
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]	
41	2593.0	40620	20	QPSK	1	0	3.71	
41	2593.0	40620	20	16QAM	1	0	3.82	
41	2593.0	40620	20	64QAM	1	0	3.53	
41	2593.0	40620	20	256QAM	1	0	3.44	
41	2593.0	40620	20	16QAM	1	50	3.90	
41	2593.0	40620	20	16QAM	1	99	3.81	
41	2593.0	40620	20	16QAM	50	0	3.57	
41	2593.0	40620	20	16QAM	100	0	3.57	
41	2593.0	40620	15	16QAM	1	36	3.88	
41	2593.0	40620	10	16QAM	1	25	3.81	
41	2593.0	40620	5	16QAM	1	12	3.77	
41	2506.0	39750	20	16QAM	1	50	3.90	
41	2549.5	40185	20	16QAM	1	50	3.90	
41	2636.5	41055	20	16QAM	1	50	3.87	
41	2680.0	41490	20	16QAM	1	50	3.95	

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup> Note: LTE TDD MIFs were taken using UL-DL Configuration 5. More information about the chosen UL-DL Configuration can be found in Section 10.

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		_					
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
48	3625.0	55990	20	QPSK	1	0	3.75
48	3625.0	55990	20	16QAM	1	0	3.90
48	3625.0	55990	20	64QAM	1	0	3.86
48	3625.0	55990	20	256QAM	1	0	3.76
48	3625.0	55990	20	16QAM	1	50	3.93
48	3625.0	55990	20	16QAM	1	99	3.89
48	3625.0	55990	20	16QAM	50	0	3.67
48	3625.0	55990	20	16QAM	100	0	3.67
48	3625.0	55990	15	16QAM	1	36	3.89
48	3625.0	55990	10	16QAM	1	25	3.89
48	3625.0	55990	5	16QAM	1	12	3.84
48	3560.0	55340	20	16QAM	1	50	3.96
48	3592.5	55665	20	16QAM	1	50	3.91
48	3657.5	56315	20	16QAM	1	50	3.91
48	3690.0	56640	20	16QAM	1	50	3.91

 Table 7-7

 LTE TDD B48 Modulation Interference Factors<sup>1,2</sup>

LTE TDD Uplink Carrier Aggregation Modulation Interference Factor<sup>1,3</sup>

				PCC							SLL				MIF (dB)				
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (UL/DL) Channel	PCC (UL/DL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	SCC (UL/DL) Channel	SCC (UL/DL) Frequency [MHz]		SCC UL# RB	SCC UL RB Offset	MIF (dB)				
CA_41C (PC3)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	3.57				
CA_41C (PC2)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	3.62				
CA_48C	LTE B48	20	55773	3603.3	16QAM	1	0	LTE B48	20	55575	3583.0	16QAM	1	99	3.81				

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup> Note: LTE TDD MIFs were taken using UL-DL Configuration 5. More information about the chosen UL-DL Configuration can be found in Section 10.

<sup>3</sup> Note: LTE TDD ULCA was evaluated to ensure LTE TDD standalone was the worst-case scenario. The configurations in Table 7-8 were determined from Tables 7-5 to 7-7 and satisfy the configuration requirements as defined in 3GPP 36.101. These MIFs were evaluated with UL-DL Configuration 5 for Power Class 3 LTE TDD and UL-DL Configuration 5 for Power Class 2 LTE TDD.

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NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n71	680.5	136100	20	DFT-s-OFDM	16QAM	1	1	-11.89
n12	707.5	141500	15	DFT-s-OFDM	16QAM	1	1	-11.94
n5	836.5	167300	20			1	-11.99	
n66	1745.0	349000	40	DFT-s-OFDM	16QAM	1	1	-11.68
n25	1882.5	376500	40	DFT-s-OFDM	16QAM	1	1	-11.51
n7	2535.0	507000	40	DFT-s-OFDM	16QAM	1	1	-11.46
n30	2310.0	462000	10	DFT-s-OFDM	16QAM	1	1	-11.83
n7	2535.0	507000	40	DFT-s-OFDM	π/2-BPSK	1	1	-15.95
n7	2535.0	507000	40	DFT-s-OFDM	QPSK	1	1	-16.38
n7	2535.0	507000	40	DFT-s-OFDM	64QAM	1	1	-9.62
n7	2535.0	507000	40	DFT-s-OFDM	256QAM	1	1	-11.12
n7	2535.0	507000	40	CP-OFDM	QPSK	1	1	-12.52
n7	2535.0	507000	40	CP-OFDM	16QAM	1	1	-11.64
n7	2535.0	507000	40	CP-OFDM	64QAM	1	1	-9.11
n7	2535.0	507000	40	CP-OFDM	256QAM	1	1	-10.29
n7	2535.0	507000	40	CP-OFDM	64QAM	1	108	-11.47
n7	2535.0	507000	40	CP-OFDM	64QAM	1	214	-11.71
n7	2535.0	507000	40	CP-OFDM	64QAM	108	0	-19.60
n7	2535.0	507000	40	CP-OFDM	64QAM	216	0	-20.36
n7	2535.0	507000	30	CP-OFDM	64QAM	1	1	-10.21
n7	2535.0	507000	25	CP-OFDM	64QAM	1	1	-10.29
n7	2535.0	507000	20	CP-OFDM	64QAM	1	1	-10.61
n7	2535.0	507000	15	CP-OFDM	64QAM	1	1	-10.18
n7	2535.0	507000	10	CP-OFDM	64QAM	1	1	-10.74
n7	2535.0	507000	5	CP-OFDM	64QAM	1	1	-10.12
n7	2520.0	504000	40	CP-OFDM	64QAM	1	1	-8.98
n7	2550.0	510000	40	CP-OFDM	64QAM	1	1	-9.08

 Table 7-9

 NR FDD Modulation Interference Factors<sup>1,2</sup>

NR TDD n41 Modulation Interference Factors<sup>1</sup>

NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	1	1	0.79
n41	2593.0	518598	100	DFT-s-OFDM	QPSK	1	1	0.76
n41	2593.0	518598	100	DFT-s-OFDM	16QAM	1	1	0.70
n41	2593.0	518598	100	DFT-s-OFDM	64QAM	1	1	0.72
n41	2593.0	518598	100	DFT-s-OFDM	256QAM	1	1	0.67
n41	2593.0	518598	100	CP-OFDM	QPSK	1	1	0.64
n41	2593.0	518598	100	CP-OFDM	16QAM	1	1	0.67
n41	2593.0	518598	100	CP-OFDM	64QAM	1	1	0.70
n41	2593.0	518598	100	CP-OFDM	256QAM	1	1	0.52
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	1	137	0.70
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	1	271	0.70
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	135	0	0.79
n41	2593.0	518598	100	DFT-s-OFDM	π/2-BPSK	270	0	0.80
n41	2593.0	518598	90	DFT-s-OFDM	π/2-BPSK	243	0	0.70
n41	2593.0	518598	80	DFT-s-OFDM	π/2-BPSK	216	0	0.75
n41	2593.0	518598	70	DFT-s-OFDM	π/2-BPSK	180	0	0.75
n41	2593.0	518598	60	DFT-s-OFDM	π/2-BPSK	162	0	0.71
n41	2593.0	518598	50	DFT-s-OFDM	π/2-BPSK	128	0	0.71
n41	2593.0	518598	40	DFT-s-OFDM	π/2-BPSK	100	0	0.74
n41	2593.0	518598	30	DFT-s-OFDM	π/2-BPSK	75	0	0.76
n41	2593.0	518598	20	DFT-s-OFDM	π/2-BPSK	50	0	0.73
n41	2546.0	509202	100	DFT-s-OFDM	π/2-BPSK	270	0	0.81
n41	2569.5	513900	100	DFT-s-OFDM	π/2-BPSK	270	0	0.80
n41	2616.5	523302	100	DFT-s-OFDM	π/2-BPSK	270	0	0.80
n41	2640.0	528000	100	DFT-s-OFDM	π/2-BPSK	270	0	0.80

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup> Note: All FDD NR bands were found to have substantially similar MIF values given similar RB, BW, and modulation configurations.

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NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n77 DoD	3500.0	633334	100	DFT-s-OFDM	π/2-BPSK	1	1	0.77
n77 DoD	3500.0	633334	100	DFT-s-OFDM	QPSK	1	1	0.76
n77 DoD	3500.0	633334	100	DFT-s-OFDM	16QAM	1	1	0.69
n77 DoD	3500.0	633334	100	DFT-s-OFDM	64QAM	1	1	0.75
n77 DoD	3500.0	633334	100	DFT-s-OFDM	256QAM	1	1	0.72
n77 DoD	3500.0	633334	100	CP-OFDM	QPSK	1	1	0.64
n77 DoD	3500.0	633334	100	CP-OFDM	16QAM	1	1	0.69
n77 DoD	3500.0	633334	100	CP-OFDM	64QAM	1	1	0.68
n77 DoD	3500.0	633334	100	CP-OFDM	256QAM	1	1	0.68
n77 DoD	3500.0	633334	100	DFT-s-OFDM	π/2-BPSK	1	137	0.78
n77 DoD	3500.0	633334	100	DFT-s-OFDM	π/2-BPSK	1	271	0.78
n77 DoD	3500.0	633334	100	DFT-s-OFDM	π/2-BPSK	135	0	0.82
n77 DoD	3500.0	633334	100	DFT-s-OFDM	π/2-BPSK	270	0	0.82
n77 DoD	3500.0	633334	90	DFT-s-OFDM	π/2-BPSK	120	0	0.81
n77 DoD	3500.0	633334	80	DFT-s-OFDM	π/2-BPSK	108	0	0.80
n77 DoD	3500.0	633334	70	DFT-s-OFDM	π/2-BPSK	90	0	0.80
n77 DoD	3500.0	633334	60	DFT-s-OFDM	π/2-BPSK	81	0	0.82
n77 DoD	3500.0	633334	50	DFT-s-OFDM	π/2-BPSK	64	0	0.81
n77 DoD	3500.0	633334	40	DFT-s-OFDM	π/2-BPSK	50	0	0.82
n77 DoD	3500.0	633334	30	DFT-s-OFDM	π/2-BPSK	36	0	0.80
n77 DoD	3500.0	633334	25	DFT-s-OFDM	π/2-BPSK	32	0	0.80
n77 DoD	3500.0	633334	20	DFT-s-OFDM	π/2-BPSK	25	0	0.81
n77 DoD	3500.0	633334	15	DFT-s-OFDM	π/2-BPSK	18	0	0.81
n77 DoD	3500.0	633334	10	DFT-s-OFDM	π/2-BPSK	12	0	0.82

# Table 7-11 NR TDD n77 DoD Modulation Interference Factors<sup>1</sup>

#### Table 7-12

## NR TDD n77 Modulation Interference Factors<sup>1</sup>

NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n77	3840.0	656000	100	DFT-s-OFDM	π/2-BPSK	1	1	0.80
n77	3840.0	656000	100	DFT-s-OFDM	QPSK	1	1	0.78
n77	3840.0	656000	100	DFT-s-OFDM	16QAM	1	1	0.75
n77	3840.0	656000	100	DFT-s-OFDM	64QAM	1	1	0.74
n77	3840.0	656000	100	DFT-s-OFDM	256QAM	1	1	0.81
n77	3840.0	656000	100	CP-OFDM	QPSK	1	1	0.68
n77	3840.0	656000	100	CP-OFDM	16QAM	1	1	0.72
n77	3840.0	656000	100	CP-OFDM	64QAM	1	1	0.63
n77	3840.0	656000	100	CP-OFDM	256QAM	1	1	0.65
n77	3840.0	656000	100	DFT-s-OFDM	256QAM	1	137	0.80
n77	3840.0	656000	100	DFT-s-OFDM	256QAM	1	271	0.80
n77	3840.0	656000	100	DFT-s-OFDM	256QAM	135	0	0.84
n77	3840.0	656000	100	DFT-s-OFDM	256QAM	270	0	0.89
n77	3840.0	656000	90	DFT-s-OFDM	256QAM	243	0	0.81
n77	3840.0	656000	80	DFT-s-OFDM	256QAM	216	0	0.88
n77	3840.0	656000	70	DFT-s-OFDM	256QAM	180	0	0.68
n77	3840.0	656000	60	DFT-s-OFDM	256QAM	162	0	0.86
n77	3840.0	656000	50	DFT-s-OFDM	256QAM	128	0	0.81
n77	3840.0	656000	40	DFT-s-OFDM	256QAM	100	0	0.81
n77	3840.0	656000	30	DFT-s-OFDM	256QAM	75	0	0.76
n77	3840.0	656000	20	DFT-s-OFDM	256QAM	50	0	0.80
n77	3840.0	656000	15	DFT-s-OFDM	256QAM	36	0	0.68
n77	3840.0	656000	10	DFT-s-OFDM	256QAM	24	0	0.81
n77	3750.0	650000	100	DFT-s-OFDM	256QAM	270	0	0.88
n77	3795.0	653000	100	DFT-s-OFDM	256QAM	270	0	0.91
n77	3885.0	659000	100	DFT-s-OFDM	DFT-s-OFDM 256QAM 270		0	0.82
n77	3930.0	662000	100	DFT-s-OFDM	256QAM	270	0	0.86

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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802.11b (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

	802.1 <sup>-</sup>	802.11b MIF Measurements [dB]								
Mode		Data Rate [Mbps]								
	1	2	5.5	11						
802.11b	-10.29	-10.29 -9.54 -7.57 -6.47								

#### Table 7-14

802.11g (2.4GHz, MIMO) Modulation Interference Factors<sup>1,2</sup>

			802.1	1g MIF Mea	asurement	s [dB]				
Mode	Data Rate [Mbps]									
12 18 24 36 48 72								108		
802.11g	-7.51	-7.51 -6.74 -6.15 -5.43 -5.06 -4.72 -4.82 -4.94								

#### Table 7-15

802.11n (2.4GHz, MIMO) Modulation Interference Factors<sup>1,2</sup>

			802.11n (2	.4GHz) MI	- Measure	ments [dB]					
Mode		MCS Index									
	0 1 2 3 4 5 6 7										
802.11n	-7.35	-7.35 -6.05 -5.47 -4.96 -4.76 -4.80 -4.91 -5.04									

#### Table 7-16

802.11ac (2.4GHz, MIMO) Modulation Interference Factors<sup>1,2</sup>

		802.11ac (2.4GHz) MIF Measurements [dB]										
Mode		MCS Index										
	0	1	2	3	4	5	6	7	8	9		
802.11ac	-6.14	6.14 -5.01 -4.79 -4.75 -5.17 -5.46 -5.61 -5.77 -6.21 -5.12										

#### Table 7-17

802.11ax (2.4GHz, SU, MIMO) Modulation Interference Factors<sup>1,2</sup>

	20MHz 802.11ax (2.4GHz) MIF Measurements [dB]											
Mode		MCS Index										
	0	1	2	3	4	5	6	7	8	9	10	11
802.11ax	-5.81											

#### 802.11ax (2.4GHz, RU, MIMO) Modulation Interference Factors<sup>1,2</sup> 20MHz 802.11ax (2.4GHz) MIF Measurements [dB] RU Index (MCS Index 2) (GI 1.6us) Mode 0 40 53 61 37 54 8 802.11ax -7.78 -7.99 -6.53 -6.76 -5.29 -5.41 -4.68

#### **Table 7-19**

802.11a (5GHz, 20MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

	802.11a MIF Measurements [dB]           Mode         Data Rate [Mbps]									
Mode										
	12 18 24 36 48 72 96 10									
802.11a	-7.52	-6.77	-6.22	-5.40	-5.04	-4.72	-4.89	-5.00		

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup>Note: WIFI MIF values were found to be independent of the transmit channel.

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#### Table 7-18

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802 11n (5GHz	20MHz BW	MIMO	Modulation	Interference Factors <sup>1,2</sup>

20MHz BW 802.11n (5GHz) MIF Measurements [dB]									
Mode	MCS Index								
	0 1 2 3 4 5 6 7								
802.11n	-7.40	-6.10	-5.45	-5.03	-4.77	-4.83	-4.93	-5.07	

# 802.11ac (5GHz, 20MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		20MHZ BW 802.11ac (5GHZ) MIF Measurements [dB]											
Mode		MCS Index											
	0	1	2	3	4	5	6	7	8	9			
802.11ac	-6.14	-5.07	-4.77	-4.85	-5.19	-5.57	-5.71	-5.85	-6.17	-5.08			

#### Table 7-22

802.11ax (5GHz, 20MHz BW, SU, MIMO) Modulation Interference Factors<sup>1,2</sup>

		20MHz 802.11ax (5GHz) MIF Measurements [dB]										
Mode		MCS Index										
	0 1 2 3 4 5 6 7 8 9 10 11									11		
802.11ax	-5.77	-4.89	-4.76	-4.79	-5.07	-5.37	-5.46	-5.64	-5.71	-5.81	-5.89	-6.07

#### Table 7-23

802.11ax (5GHz, 20MHz BW, RU, MIMO) Modulation Interference Factors<sup>1,2</sup>

	20MHz 802.11ax (5GHz) MIF Measurements [dB]										
Mode	RU Index (MCS Index 2) (GI 1.6us)										
	0 8 37 40 53 54										
802.11ax	-7.71	-7.71 -7.83 -6.61 -6.65 -5.35 -5.34 -4.66									

#### Table 7-24

802.11n (5GHz, 40MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		40MHz BW 802.11n (5GHz) MIF Measurements [dB]									
Mode		MCS Index									
	0 1 2 3 4 5 6 7										
802.11n	-5.93	-4.87	-4.66	-4.77	-5.26	-5.75	-5.91	-6.10			

#### Table 7-25

802.11ac (5GHz, 40MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

	40MHz BW 802.11ac (5GHz) MIF Measurements [dB]										
Mode		MCS Index									
	0 1 2 3 4 5 6 7 8 9									9	
802.11ac	-4.87	-4.73	-5.15	-5.61	-6.10	-6.61	-6.76	-6.92	N/A	-7.21	

#### Table 7-26

802.11ax (5GHz, 40MHz BW, SU, MIMO) Modulation Interference Factors<sup>1,2</sup>

		40MHz 802.11ax (5GHz) MIF Measurements [dB]											
Mode		MCS Index											
	0	1	2	3	4	5	6	7	8	9	10	11	
802.11ax	-4.75	-4.67	-5.00	-5.32	-5.66	-5.96	-6.03	-6.11	-6.35	-6.35	-6.37	-6.36	

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup>Note: WIFI MIF values were found to be independent of the transmit channel.

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802.11ax (5GHz, 40MHz BW, RU, MIMO) Modulation Interference Factors<sup>1,2</sup>

	•	40MHz 802.11ax (5GHz) MIF Measurements [dB]								
Mode		RU Index (MCS Index 1) (GI 1.6us)								
	0	0 17 37 44 53 56 61 62 65								
802.11ax	-8.44									

802.11ac (5GHz, 80MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		80MHz BW 802.11ac (5GHz) MIF Measurements [dB]									
Mode		MCS Index									
	0	1	2	3	4	5	6	7	8	9	
802.11ac	-4.79	-5.64	-6.16	-6.57	-7.00	-7.31	-7.30	-7.47	-7.47	-7.63	

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802.11ax (5GHz, 80MHz BW, SU, MIMO) Modulation Interference Factors<sup>1,2</sup>

		80MHz 802.11ax (5GHz) MIF Measurements [dB]										
Mode		MCS Index										
	0	0 1 2 3 4 5 6 7 8 9 10 11										
802.11ax	-4.74	-5.37	-5.67	-6.01	-6.19	-6.47	-6.46	-6.47	-6.69	-6.67	-6.67	-6.70

#### Table 7-30

802.11ax (5GHz, 80MHz BW, RU, MIMO) Modulation Interference Factors<sup>1,2</sup>

		80MHz 802.11ax (5GHz) MIF Measurements [dB]								
Mode		RU Index (MCS Index 0) (GI 1.6us)								
	0	0 36 37 52 53 60 61 64 65 66 67								
802.11ax	-9.44	-9.44 -9.50 -8.47 -8.62 -7.23 -7.26 -5.73 -5.72 -4.68 -4.71 -4.62								

#### Table 7-31

802.11ac (5GHz, 160MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		160MHz BW 802.11ac (5GHz) MIF Measurements [dB]								
Mode		MCS Index								
	0	0 1 2 3 4 5 6 7 8 9								
802.11ac	-5.75	-6.67	-7.06	-7.37	-7.49	-7.64	-7.65	-7.80	-7.81	-7.81

#### Table 7-32

802.11ax (5GHz, 160MHz BW, SU, MIMO) Modulation Interference Factors<sup>1,2</sup>

	160MHz 802.11ax (5GHz) MIF Measurements [dB]											
Mode		MCS Index										
	0	0 1 2 3 4 5 6 7 8 9 10 11										
802.11ax	-5.33	-5.97	-6.15	-6.44	-6.52	-6.65	-6.65	-6.65	-6.65	-6.66	-6.81	-6.79

#### Table 7-33

802.11ax (5GHz, 160MHz BW, RU, MIMO) Modulation Interference Factors<sup>1,2</sup>

		160MHz 802.11ax (5GHz) MIF Measurements [dB]									
Mode		RU Index (MCS Index 0) (GI 1.6us)									
	0 36 37 52 53 60 61 64 65 66 67								67		
802.11ax	-9.37	-9.44	-8.43	-8.54	-7.25	-7.27	-5.77	-5.74	-4.67	-4.71	-4.66

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup> Note: WIFI MIF values were found to be independent of the transmit channel.

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#	5 GHz [dE	z WIFI 3m]	2.4 GH [dE	Iz WIFI 3m]	Measured MIF (dB)
Тх	Ant1	- Ant2	Ant1	- Ant2	
3	x	х	x	-	-6.33
3	х	х	-	х	-7.00
4	x	х	x	х	-5.58

 Table 7-34

 Simultaneous 2.4GHz and 5GHz WIFI Modulation Interference Factors<sup>1,2,3</sup>

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>2</sup> Note: WLAN MIF values were found to be independent of the transmit channel.

<sup>3</sup> Note: The configuration for each scenario (e.g. bandwidth, data rate, etc.) was determined using the worst-case configuration from SISO and MIMO MIF measurements.

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#### 8. CONDUCTED POWER CONFIGURATIONS AND TARGETS

#### I. Procedures Used to Establish RF Signal for HAC Testing

The handset was configured to transmit the required air interface in a shielded chamber. Measurements were taken with a fully charged battery.

#### II. **HAC Target Powers**

All applicable modes supported by the device have their held-to-ear conducted power targets listed below and were used for the individual mode evaluations in Section 9. All conducted power targets have a tolerance of +1.0dB and -1.5dB unless otherwise noted. For WIFI modes, the overall maximum power amongst all bands per IEEE standards is listed. Additionally, this model has no lower tolerance for WIFI mode target powers.

#### III. **RF Conducted Power Measurement Setup and Conditions**

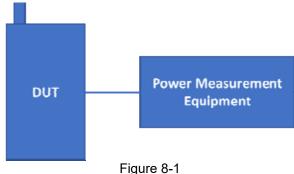
## **Output Power Verification**

Maximum output power is verified for all applicable test channels for all air interfaces which require test scans. See Table 8-1 for air interface specific settings of transmit power parameters. See Table 9-1 for more information regarding which modes required test scans and had conducted power measurements taken.

Power Control Parameters and Settings by Air Interface				
Air Interface:	Parameter Name:	Parameter Set To:		
GSM	PCL	GSM850: "5"; GSM1900: "0"		
UMTS	TPC	"All 1's"		
LTE	TPC	"Max Power"		
NR	PLS	Mfr Specified		
WIFI	PLS	Mfr Specified		

Table 8-1

The general setup for conducted powers included in Section 11 is shown in Figure 8-1 below. The power measurement equipment could be a base station simulator, signal analyzer, or power meter depending on the applicable air interface.



Power Measurement Setup

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## IV. GSM Target Powers

GSM Conducted Power Targets			
Band	Modulated Average Output Power (in dBm)		
Danu	Voice	Data	
GSM/EDGE 850	32.0	27.0	
GSM/EDGE 1900	29.0	26.0	

## Table 8-2 GSM Conducted Power Targets

## V. UMTS Target Powers

#### Table 8-3 UMTS Conducted Power Targets

Band	Modulated Average Output Power (in dBm)		
Danu	3GPP WCDMA Rel 99	3GPP HSUPA Rel 6	
UMTS V	24.0	23.0	
UMTS IV	23.0	22.0	
UMTS II	23.0	22.0	

## VI. LTE FDD Target Powers

# Table 8-4 LTE FDD Conducted Power Targets

Band	Modulated Average Output Power (in dBm)
LTE Band 71	24.8
LTE Band 12	24.8
LTE Band 13	24.5
LTE Band 14	24.5
LTE Band 5	24.8
LTE Band 26	24.8
LTE Band 4	23.5
LTE Band 66	23.5
LTE Band 2	23.5
LTE Band 25	23.5
LTE Band 30	22.5
LTE Band 7	23.0

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 Table 8-5

 LTE FDD Uplink Carrier Aggregation Conducted Power Targets

	Modulated Average Output Power (in dBm)
LTE Band 5	24.8
LTE Band 66	23.5

## VII. LTE TDD Target Powers

Table 8-6 LTE TDD Conducted Power Targets			
Band	Modulated Average Output Power (in dBm)		
LTE Band 38	24.0		
LTE Band 41 PC3	24.0		
LTE Band 41 PC2	26.5		
LTE Band 48	23.0		

 Table 8-7

 LTE TDD Uplink Carrier Aggregation Conducted Power Targets

Band	Modulated Average Output Power (in dBm)
LTE Band 41 PC3	24.0
LTE Band 41 PC2	26.5
LTE Band 48	23.0

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## VIII. NR FDD Target Powers

NR FDD Conducted	d Power Targets
Band	Modulated Average Output Power (in dBm)
NR Band n71	24.5
NR Band n12	24.5
NR Band n5	24.5
NR Band n66	23.5
NR Band n2	23.5
NR Band n25	23.5
NR Band n30	22.5
NR Band n7	23.0

# Table 8-8 NR FDD Conducted Power Targets

## IX. NR TDD Target Powers

Table 8-9 NR TDD Conducted Power Targets

Band	Modulated Average Output Power (in dBm)
NR Band n38	24.0
NR Band n41	26.0
NR Band n77	26.0
NR Band n77 (DoD)	26.0

## X. WIFI Target Powers

# Table 8-10 IEEE 802.11a/b/g/n/ac/ax Reduced Average RF Power Targets<sup>1</sup>

Band	Modulated Average Output Power (in dBm)
WLAN - 2.4GHz	19.0
WLAN - 5GHz	16.0
WLAN - RSDB	19.0

<sup>1</sup> Note: This device utilizes independent power reduction mechanisms for the WIFI transmitter in all WIFI modes for held-to-ear scenarios.

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#### JUSTIFICATION OF HELD TO EAR MODES TESTED 9.

#### I. Analysis of RF Air Interface Technologies

An analysis was performed, following the guidance of §4.3 and §4.4 of the ANSI standard, of the RF air interface technologies being evaluated. The factors that will affect the RF interference potential were evaluated, and the worst-case operating modes were identified and used in the evaluation. A WD's interference potential is a function both of the WD's average near-field field strength and of the signal's audio-frequency amplitude modulation characteristics. Per §4.4, RF air interface technologies that have low power have been found to produce sufficiently low RF interference potential, so it is possible to exempt them from the product testing specified in Clause 5 of the ANSI standard. An RF air interface technology of a device is exempt from testing when its average antenna input power plus its MIF is ≤17dBm for all of its operating modes. RF air interface technologies exempted from testing in this manner are automatically assigned an M4 rating to be used in determining the overall rating for the WD.

The worst-case MIF plus the worst-case average antenna input power for all modes are investigated below to determine the testing requirements for this device.

#### II. Individual Mode Evaluations

Max Power + MIF calculations for Low Power Exemptions							
Air Interface	Maximum Average Power (dBm)	Worst Case MIF (dB)	Total (Power + MIF, dB)	C63.19 Testing Required			
GSM - GSM850	23.81*	3.58	27.39	Yes			
GSM - GSM1900	20.81*	3.58	24.39	Yes			
GSM - EDGE850	18.81*	3.82	22.63	Yes***			
GSM - EDGE1900	17.81*	3.76	21.57	Yes***			
UMTS - RMC	25.00	-23.79	1.21	No			
UMTS - AMR	25.00	-24.04	0.96	No			
UMTS - HSPA	24.00	-21.08	2.92	No			
LTE FDD	25.80	-9.29	16.51	No			
LTE FDD - Uplink Carrier Aggregation	25.80	-9.74	16.06	No			
LTE TDD - Band 41 (PC3)	15.29*	3.88	19.17	Yes			
LTE TDD - Band 41 (PC2)	17.79*	3.95	21.74	Yes			
LTE TDD - Band 48	14.29*	3.96	18.25	Yes			
LTE TDD - Uplink Carrier Aggregation	17.79*	3.62	21.41	Yes****			
NR FDD	25.50	-8.98	16.52	No			
NR TDD - n41	20.98*	0.81	21.79	Yes			
NR TDD - n77 (DoD)	20.98*	0.82	21.80	Yes			
NR TDD - n77	20.98*	0.91	21.89	Yes			
WIFI - 2.4GHz	20.00	-4.68	15.32	No			
WIFI - 5GHz	17.00	-4.59	12.41	No			
Simultaneous 2.4GHz and 5GHz WIFI Operations	20.01**	-5.58	14.43	No			

Table 9-1 defiere famlieur Deuren Eurenstiere

\* Note: ANSI C63.19-2011 Sec. 4.4 Footnote 20 indicates the use of a long averaging time for measuring the antenna input power when using this method of exclusion. Therefore, the frame averaged power was calculated for these modes in this investigation.

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\*\* Note: This value is calculated as the linear sum of the worst-case power for each band and antenna combination while in simultaneous 2.4GHz and 5GHz operation. This calculation is conservative and for use in this investigation only.

\*\*\* Note: EDGE data modes were considered but not tested as GSM voice modes were found to be the worst-case modes for the GSM air interface.

\*\*\*\* Note: LTE ULCA data modes were considered but not tested as LTE standalone data modes were found to be the worst-case modes for the LTE air interface.

## III. Low-Power Exemption Conclusions

Per ANSI C63.19-2011, RF Emissions testing for this device is required only for GSM voice mode as well as LTE TDD (Power Class 3 and Power Class 2) and NR TDD data modes. All other air interfaces are exempt.

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# **10. LTE TDD UPLINK-DOWNLINK CONFIGURATION**

## I. Uplink-Downlink Configuration Additional Testing

Additional testing was performed on each supported power class for LTE TDD to determine the worst-case Uplink-Downlink configuration for RFE testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length  $T_f = 307200 \cdot T_s = 10$  ms, where  $T_s$  is a number of time units equal to 1/(15000 x 2048) seconds. Additionally, each radio frame consists of 10 subframes, each of length  $30720 \cdot T_s = 1$  ms, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is 2192  $\cdot$  Ts which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

Uplink-downlink configuration	Downlink-to-Uplink Switch-point periodicity				Calculated Transmission							
-		0	1	2	3	4	5	6	7	8	9	Duty Cycle (%)
0	5 ms	D	S	υ	υ	U	D	S	U	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	U	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	U	D	D	21.4%
3	10 ms	D	S	υ	υ	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

 Table 10-1

 Uplink-Downlink Configurations for Type 2 Frame Structures

## II. Power Class 3 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, QPSK, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-2 below for results. The configuration determined in the results below was used to measure the MIF values in table 7-5 and 7-7.

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissio	ons														
	20	40620	0	QPSK	1	0	Acoustic	12.98	22.27	-3.34	18.93	35.00	-16.07	M4	4,7,8
	20	40620	1	QPSK	1	0	Acoustic	11.59	21.28	-1.60	19.68	35.00	-15.32	M4	6,8,9
	20	40620	2	QPSK	1	0	Acoustic	10.26	20.22	1.47	21.69	35.00	-13.31	M4	1,4,7
LTE TDD / Band 41	20	40620	3	QPSK	1	0	Acoustic	10.88	20.73	-1.49	19.24	35.00	-15.76	M4	4,7,8
	20	40620	4	QPSK	1	0	Acoustic	10.35	20.30	0.61	20.91	35.00	-14.09	M4	1,4,7
	20	40620	5	QPSK	1	0	Acoustic	9.62	19.66	3.63	23.29	35.00	-11.71	M4	1,4,7
	20	40620	6	QPSK	1	0	Acoustic	12.11	21.66	-2.54	19.12	35.00	-15.88	M4	4,7,8

Table 10-2									
LTE TDD Power Class 3 UL-DL Configuration Results									
							Audio		

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## III. Power Class 2 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, QPSK, 1RB, 0RB Offset. For Power Class 2, only configurations 1-5 are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-3 below for results. The configuration determined in the results below was used to measure the MIF values in Table 7-6.

	-		l		עעו	POW	er Clas	<u>s z ul-</u>		iligurau	on Res	uits			
Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissio	Field Emissions														
	20	40620	1	QPSK	1	0	Acoustic	13.31	22.48	-1.64	20.84	35.00	-14.16	M4	4,7,8
	20	40620	2	QPSK	1	0	Acoustic	11.13	20.93	1.49	22.42	35.00	-12.58	M4	4,7,8
LTE TDD / Band 41	20	40620	3	QPSK	1	0	Acoustic	12.05	21.62	-1.49	20.13	35.00	-14.87	M4	1,4,7
	20	40620	4	QPSK	1	0	Acoustic	11.00	20.83	0.62	21.45	35.00	-13.55	M4	1,4,7
	20	40620	5	QPSK	1	0	Acoustic	9.51	19.56	3.69	23.25	35.00	-11.75	M4	1,4,7



#### IV. Conclusion

Per the results above, UL-DL Configuration 5 was used for both LTE TDD Power Class 3 and LTE TDD Power Class 2 testing.

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# 11. OVERALL MEASUREMENT SUMMARY

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## I. E-FIELD EMISSIONS:

HAC Data Summary for GSM E-field													
Mode	Channel	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5		
E-Field Emissio	E-Field Emissions												
	128	Acoustic	31.67	30.00	29.54	3.58	33.12	45.00	-11.88	M4	7,8,9		
GSM850	190	Acoustic	32.12	30.42	29.66	3.58	33.24	45.00	-11.76	M4	4,7,8		
	251	Acoustic	31.96	30.63	29.72	3.58	33.30	45.00	-11.70	M4	7,8,9		
	512	Acoustic	28.92	8.97	19.06	3.57	22.63	35.00	-12.37	M4	1,2,3		
GSM1900	661	Acoustic	29.00	9.23	19.30	3.58	22.88	35.00	-12.12	M4	1,2,3		
	810	Acoustic	28.86	9.64	19.68	3.58	23.26	35.00	-11.74	M4	1,2,3		

Table 11-1 HAC Data Summary for GSM E-field

 Table 11-2

 HAC Data Summary for LTE TDD Band 41 (Power Class 3) E-field

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissio	E-Field Emissions															
	20	39750	5	QPSK	1	0	Acoustic	23.66	8.26	18.34	3.79	22.13	35.00	-12.87	M4	2,3,6
	20	40185	5	QPSK	1	0	Acoustic	23.63	7.83	17.88	3.78	21.66	35.00	-13.34	M4	1,4,7
LTE TDD / Band 41 PC3	20	40620	5	QPSK	1	0	Acoustic	23.21	7.61	17.63	3.88	21.51	35.00	-13.49	M4	1,4,7
	20	41055	5	QPSK	1	0	Acoustic	23.28	8.17	18.24	3.78	22.02	35.00	-12.98	M4	4,7,8
	20	41490	5	QPSK	1	0	Acoustic	23.08	8.24	18.32	3.82	22.14	35.00	-12.86	M4	7,8,9

 Table 11-3

 HAC Data Summary for LTE TDD Band 41 (Power Class 2) E-field

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissio	E-Field Emissions															
	20	39750	5	QPSK	1	0	Acoustic	26.11	9.40	19.46	3.90	23.36	35.00	-11.64	M4	2,3,6
	20	40185	5	QPSK	1	0	Acoustic	25.97	8.80	18.89	3.90	22.79	35.00	-12.21	M4	1,4,7
LTE TDD / Band 41 PC2	20	40620	5	QPSK	1	0	Acoustic	25.68	9.17	19.25	3.90	23.15	35.00	-11.85	M4	6,8,9
	20	41055	5	QPSK	1	0	Acoustic	25.70	9.65	19.69	3.87	23.56	35.00	-11.44	M4	6,8,9
	20	41490	5	QPSK	1	0	Acoustic	25.54	9.74	19.77	3.95	23.72	35.00	-11.28	M4	1,4,7

 Table 11-4

 HAC Data Summary for LTE TDD Band 48 E-field

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissie	E-Field Emissions															
	20	55340	5	QPSK	1	0	Acoustic	22.27	14.13	23.00	3.96	26.96	35.00	-8.04	M4	2,3,6
	20	55665	5	QPSK	1	0	Acoustic	22.46	14.68	23.33	3.91	27.24	35.00	-7.76	M4	2,3,6
LTE TDD / Band 48	20	55990	5	QPSK	1	0	Acoustic	22.56	13.90	22.86	3.93	26.79	35.00	-8.21	M4	2,3,6
	20	56315	5	QPSK	1	0	Acoustic	22.22	12.94	22.24	3.91	26.15	35.00	-8.85	M4	1,2,3
	20	56640	5	QPSK	1	0	Acoustic	22.14	12.19	21.72	3.91	25.63	35.00	-9.37	M4	1,2,3

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Table 11-5								
HAC Data Summary for NR TDD n41 E-field								

Mode / Band	Bandwidth (MHz)	Channel	Waveform	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissio	-Field Emissions															
	100	509202	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	24.99	39.95	32.03	0.81	32.84	35.00	-2.16	M3	6,8,9
	100	513900	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.50	39.54	31.94	0.80	32.74	35.00	-2.26	M3	6,8,9
NR TDD / n41	100	518598	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.43	39.72	31.98	0.80	32.78	35.00	-2.22	M3	6,8,9
NK IDD/II41	100	523302	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.32	38.77	31.77	0.80	32.57	35.00	-2.43	M3	6,8,9
	100	528000	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.40	38.33	31.67	0.80	32.47	35.00	-2.53	M3	6,8,9
	100	509202	DFT-s-OFDM	π/2-BPSK	1	1	T-Coil	24.99	35.28	30.95	0.81	31.76	35.00	-3.24	M3	6,8,9

Table 11-6 HAC Data Summary for NR TDD n77 DoD E-field

Mode / Band	Bandwidth (MHz)	Channel	Waveform	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissio	E-Field Emissions															
NR TDD / n77 (DoD)	100	633334	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.07	16.56	24.38	0.82	25.20	35.00	-9.80	M4	1,2,3

Table 11-7 HAC Data Summary for NR TDD n77 E-field

Mode / Band	Bandwidth (MHz)	Channel	Waveform	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissions																
	100	650000	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	24.96	23.42	27.39	0.88	28.27	35.00	-6.73	M4	1,2,3
	100	653000	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.10	24.46	27.77	0.91	28.68	35.00	-6.32	M4	1,2,3
NR TDD / n77	100	656000	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.27	24.07	27.63	0.89	28.52	35.00	-6.48	M4	1,2,3
	100	659000	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	24.98	22.36	26.99	0.82	27.81	35.00	-7.19	M4	1,2,3
	100	662000	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	25.14	20.56	26.26	0.86	27.12	35.00	-7.88	M4	1,2,3



**Figure 11-1** Sample E-field Scan Overlay (See Test Setup Photographs for actual WD overlay.)

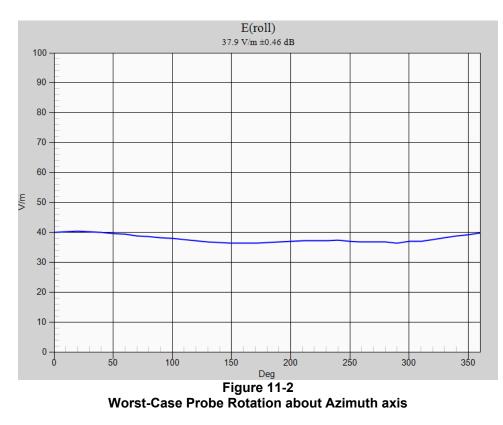
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## II. Worst-case Configuration Evaluation

	Peak Reading 360° Probe Rotation at Azimuth axis														
Mode	Bandwidth (MHz)	Channel	Waveform	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
Probe Rotation	Probe Rotation at Worst-Case														
NR TDD / n41	100	509202	DFT-s-OFDM	π/2-BPSK	1	1	Acoustic	40.38	32.12	0.81	32.93	35.00	-2.07	M3	6,8,9

 Table 11-8

 Peak Reading 360° Probe Rotation at Azimuth axis



\* Note: Locations of probe rotation (with and without exclusions) are shown in Figure 11-1 denoted by the green square markers.

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## 12. EQUIPMENT LIST

## Table 12-1 Equipment List

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4438C	ESG Vector Signal Generator	9/28/2021	Annual	9/28/2022	MY45091346
Agilent	N5182A	MXG Vector Signal Generator	7/6/2021	Annual	7/6/2022	MY48180366
leysight Technologie	N9020A	MXA Signal Analyzer	2/24/2021	Annual	2/24/2022	MY48010233
Amplifier Research	15S1G6	Amplifier	N/A	CBT*	N/A	433978
Anritsu	MA2411B	Pulse Power Sensor	3/8/2021	Annual	3/8/2022	1339007
Anritsu	MA2411B	Pulse Power Sensor	3/9/2021	Annual	3/9/2022	1207470
Anritsu	MA24106A	USB Power Sensor	8/10/2021	Annual	8/10/2022	1231538
Anritsu	MA24106A	USB Power Sensor	8/10/2021	Annual	8/10/2022	1231535
Anritsu	ML2496A	Power Meter	2/19/2021	Annual	2/19/2022	1138001
Control Company	4040	Therm./ Clock/ Humidity Monitor	3/6/2020	Biennial	3/6/2022	200170289
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	N/A	CBT*	N/A	1226
Pasternack	PE2237-20	Bidirectional Coupler	N/A	CBT*	N/A	N/A
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	2/10/2021	Annual	2/10/2022	161662
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	3/22/2021	Annual	3/22/2022	162125
Rohde & Schwarz	CMW500	Radio Communication Tester	9/30/2021	Annual	9/30/2022	140144
Rohde & Schwarz	CMW500	Radio Communication Tester	7/19/2021	Annual	7/19/2022	128635
Seekonk	NC-100	Torque Wrench (8" lb)	8/4/2020	Biennial	8/4/2022	N/A
SPEAG	AIA	Audio Interference Analzyer	N/A	CBT*	N/A	1010
SPEAG	EF3DV3	Freespace E-field Probe	2/15/2021	Biennial	2/15/2023	4035
SPEAG	CD835V3	Freespace 835 MHz Dipole	1/14/2021	Biennial	1/14/2023	1003
SPEAG	CD1880V3	Freespace 1880 MHz Dipole	1/14/2021	Biennial	1/14/2023	1137
SPEAG	CD2600V3	/3 Freespace 2600MHz Dipole		Biennial	1/14/2023	1012
SPEAG	CD3500V3 Freespace 3500 MHz Dipole		10/20/2020	Biennial	10/20/2022	1005
SPEAG	SPEAG CD3500V3 Freespace 3500 MHz Dipole		3/2/2021	Biennial	3/2/2023	1015
SPEAG	SPEAG DAE4 Dasy Data Acquisition Electronics		1/13/2021	Annual	1/13/2022	1530

Calibration traceable to the National Institute of Standards and Technology (NIST).

\*Note: CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

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## **13. MEASUREMENT UNCERTAINTY**

## Table 13-1

Uncertainty Estimation Table

Wireless Communications Device Near-Field Measurement Uncertainty Estimation										
Uncertainty Component	Data (dB)	Data Type	Prob. Dist.	Divisor	Ci (E)	Unc. (dB)	Notes/Comments			
Measurement System	8									
RF System Reflections	0.50	Tolerance	Ν	1.00	1	0.50	* Refl. < -20 dB			
Field Probe Calibration	0.21	Tolerance	Ν	1.00	1	0.21				
Field Probe Isotropy	0.01	Tolerance	Ν	1.00	1	0.01				
Field Probe Frequency Response	Tolerance	Ν	1.00	1	0.14					
Field Probe Linearity	eld Probe Linearity 0.013 Tolerance N 1									
Modulation Interference Factor	0.20	Tolerance	R	1.73	1	0.12	Applicable for M-rating testing			
Boundary Effects	0.105	Accuracy	R	1.73	1	0.06	*			
Probe Positioning Accuracy	0.20	Accuracy	R	1.73	1	0,12	*			
Probe Positioner	0.050	Accuracy	R	1.73	1	0.03	*			
Extrapolation/Interpolation	0.045	Tolerance	R	1.73	1	0.03	*			
Resolution to 2mm error	0.21	Tolerance	Ν	1.00	1	0.21				
System Detection Limit	0.05	Tolerance	R	1.73	1	0.03	*			
Readout Electronics	0.015	Tolerance	Ν	1.00	1	0.02	*			
Integration Time	0.11	Tolerance	R	1.73	1	0.06	*			
Response Time	0.033	Tolerance	R	1.73	1	0.02	*			
Phantom Thickness	0.10	Tolerance	R	1.73	1	0.06	*			
System Repeatability (Field x 2=power)	0.17	Tolerance	Ν	1.00	1	0.17	*			
Test Sample Related		•					•			
Device Positioning Vertical	0.2	Tolerance	R	1.73	1	0.12	*			
Device Positioning Lateral	0.045	Tolerance	R	1.73	1	0.03	*			
Device Holder and Phantom	0.1	Tolerance	R	1.73	1	0.06	*			
Power Drift	0.21	Tolerance	R	1.73	1	0.12				
Combined Standard Uncertainty (k=1)			0.66	16.3%						
Expanded Uncertainty [95% confidence]		1.31	32.6%							
Expanded Uncertainty [95% confidence]		0.66	16.3%							

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

2. \* Uncertainty specifications from Schmidt & Partner Engineering AG (not site specific)

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurements (so-called Type A uncertainty). This may mean that the Hearing Aid immunity tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurements to identify the measurement uncertainty. By combining the repeat measurements with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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## 14. TEST DATA

See following Attached Pages for Test Data.

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## DUT: CD835V3 - SN1003

Type: CD835V3 Serial: 1003

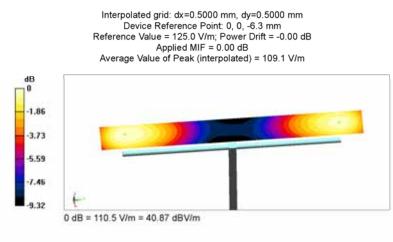
#### **Communication System: CW; Frequency: 835 MHz;**

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## 835 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x361x1):



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## DUT: CD1880V3 - SN1137

Type: CD1880V3 Serial: 1137

#### **Communication System: CW; Frequency: 1880 MHz;**

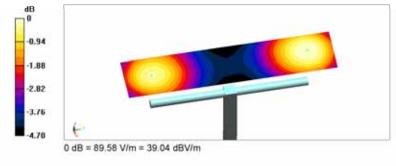
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- · Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## 1880 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 161.5 V/m; Power Drift = -0.05 dB Applied MIF = 0.00 dB Average Value of Peak (interpolated) = 88.3 V/m



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## DUT: CD2600V3 - SN1012

Type: CD2600V3 Serial: 1012

#### Communication System: CW (0); Frequency: 2600 MHz;

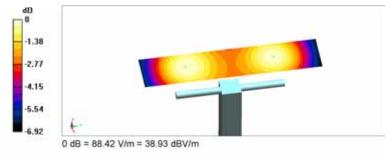
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- · Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## 2600 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 67.35 V/m; Power Drift = -0.03 dB Applied MIF = 0.00 dB Average Value of Peak (interpolated) = 87.9 V/m



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## DUT: CD2600V3 - SN1012

Type: CD2600V3 Serial: 1012

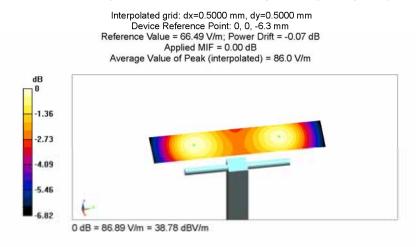
#### Communication System: CW; Frequency: 2600 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

#### 2600 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):



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## DUT: CD3500V3 - SN1005

Type: CD3500V3 Serial: 1005

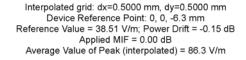
#### **Communication System: CW; Frequency: 3500 MHz;**

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## 3500 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):





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## DUT: CD3500V3 - SN1015

Type: CD3500V3 Serial: 1015

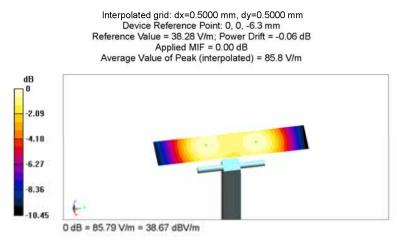
#### **Communication System: CW; Frequency: 3500 MHz;**

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- · Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);
- , (),

## 3500 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):



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## DUT: CD3500V3 - SN1015

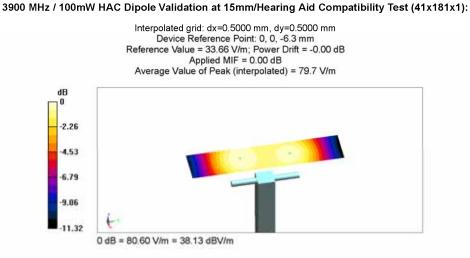
Type: CD3500V3 Serial: 1015

#### **Communication System: CW; Frequency: 3900 MHz;**

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);



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## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:8.3

## Communication System: GSM; Frequency: 848.8 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## GSM850 High Channel / Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 41.64 V/m; Power Drift = -0.03 dB Applied MIF = 3.58 dB RF audio interference level = 33.30 dBV/m Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
32.19 dBV/m	32.59 dBV/m	31.64 dBV/m
Grid 4 M4 32.81 dBV/m		Grid 6 M4 32.67 dBV/m
		Grid 9 M4 33.28 dBV/m



0 dB = 51.26 V/m = 34.20 dBV/m

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## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:8.3

## Communication System: GSM; Frequency: 1909.8 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

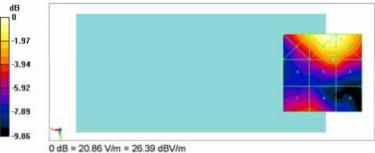
- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## GSM1900 High Channel / Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 9.264 V/m; Power Drift = -0.19 dB Applied MIF = 3.58 dB RF audio interference level = 23.26 dBV/m Emission category: M4

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
24.69 dBV/m	26.39 dBV/m	26.22 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
20.83 dBV/m	23.26 dBV/m	23.14 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
22.33 dBV/m	22.3 dBV/m	19.52 dBV/m



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## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:9.35

## Communication System: LTE Band 41; Frequency: 2680 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## TDD LTE PC3 Band 41 High Channel, UL-DL 5, 20MHz BW, QPSK, 1RB, 0RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 10.08 V/m; Power Drift = -0.06 dB Applied MIF = 3.82 dB RF audio interference level = 22.14 dBV/m **Emission category: M4** 

## MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
22.06 dBV/m	21.93 dBV/m	21.28 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
22.02 dBV/m	22.14 dBV/m	21.8 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
21.89 dBV/m	22.23 dBV/m	22.07 dBV/m



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## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:9.35

## Communication System: LTE Band 41; Frequency: 2680 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

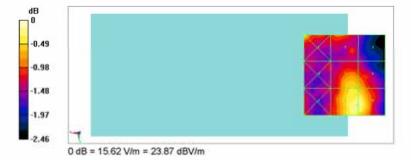
- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## TDD LTE PC2 Band 41 High Channel, UL-DL 5, 20MHz BW, QPSK, 1RB, 0RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 11.17 V/m; Power Drift = 0.15 dB Applied MIF = 3.95 dB RF audio interference level = 23.72 dBV/m **Emission category: M4** 

## MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
23.87 dBV/m	23 dBV/m	22.46 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
22.66 dBV/m	23.4 dBV/m	23.29 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
23.1 dBV/m	23.72 dBV/m	23.72 dBV/m



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## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:9.35

#### Communication System: LTE Band 48; Frequency: 3592.5 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## TDD LTE Band 48 Low Mid Channel, UL-DL 5, 20MHz BW, QPSK, 1RB, 0RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 22.17 V/m; Power Drift = -0.06 dB Applied MIF = 3.91 dB RF audio interference level = 27.24 dBV/m **Emission category: M4** 

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
26.1 dBV/m	26.97 dBV/m	26.95 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
25.5 dBV/m	27.24 dBV/m	27.14 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
25.5 dBV/m	27.08 dBV/m	26.54 dBV/m



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PCTEST Hearing-Aid Compatibility Facility

## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:4

## Communication System: NR n41; Frequency: 2546.01 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

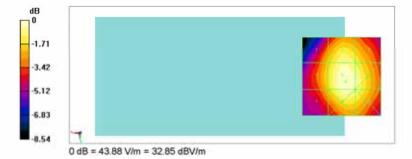
- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## NR n41 PC2 Low Channel, 100MHz BW, DFT-s-OFDM, π/2-BPSK, 1RB, 1RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 59.84 V/m; Power Drift = -0.04 dB Applied MIF = 0.81 dB RF audio interference level = 32.84 dBV/m **Emission category: M3** 

## MIF scaled E-field

Grid 1 M3	Grid 2 M3	Grid 3 M3
30.86 dBV/m	32.22 dBV/m	31.68 dBV/m
Grid 4 M3	Grid 5 M3	Grid 6 M3
31.25 dBV/m	32.84 dBV/m	32.42 dBV/m
Grid 7 M3	Grid 8 M3	Grid 9 M3
30.8 dBV/m	32.6 dBV/m	32.2 dBV/m



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PCTEST Hearing-Aid Compatibility Facility

## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:4

## Communication System: NR n77; Frequency: 3500.01 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

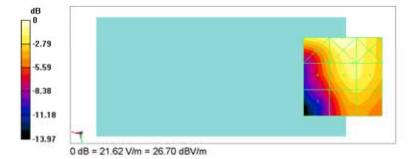
- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## NR n77 DoD Mid Channel, 100MHz BW, DFT-s-OFDM, π/2-BPSK, 1RB, 1RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 21.41 V/m; Power Drift = 0.07 dB Applied MIF = 0.82 dB RF audio interference level = 25.20 dBV/m **Emission category: M4** 

## MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
26.14 dBV/m	26.7 dBV/m	25.99 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
22.97 dBV/m	25.2 dBV/m	25.14 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
20.79 dBV/m	24.13 dBV/m	24.13 dBV/m



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PCTEST Hearing-Aid Compatibility Facility

## DUT: A3LSMS906U

Type: Portable Handset Serial: 0271M Backlight off Duty Cycle: 1:4

## Communication System: NR n77; Frequency: 3795 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 2/15/2021
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1530; Calibrated: 1/13/2021
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (4);

## NR n77 Low Mid Channel, 100MHz BW, DFT-s-OFDM, π/2-BPSK, 1RB, 1RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 32.53 V/m; Power Drift = 0.15 dB Applied MIF = 0.91 dB RF audio interference level = 28.68 dBV/m **Emission category: M4** 

## MIF scaled E-field

Grid 1 M4	Grid 2 M3	Grid 3 M4
29.67 dBV/m	30.29 dBV/m	29.57 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
26.58 dBV/m	28.68 dBV/m	28.59 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
25.16 dBV/m	27.4 dBV/m	27.39 dBV/m



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# **15. CALIBRATION CERTIFICATES**

The following pages include the probe calibration used to evaluate HAC for the DUT.

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Calibration Laboratory of
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Zeughausstrasse 43, 8004 Zurich, Switzerland



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Accreditation No.: SCS 0108

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Client PC Test		Certificate No:	EF3_4035_Feb21
CALIBRATION	CERTIFICATE		
Object	EF3DV3- SN:403	5	
Calibration procedure(s)	QA CAL-02.v9, Q/ Calibration proced evaluations in air	A CAL-25.v7 lure for E-field probes optimized f	for close near field
Calibration date:	February 15, 2021		
The measurements and the uno	certainties with confidence pro ucted in the closed laboratory	aal standards, which realize the physical units bability are given on the following pages and facility: environment temperature $(22 \pm 3)^{\circ}$ C :	are part of the certificate.
Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	01-Apr-20 (No. 217-03100/03101)	Apr-21
Power sensor NRP-Z91	SN: 103244	01-Apr-20 (No. 217-03100)	Apr-21
Power sensor NRP-Z91	SN: 103245	01-Apr-20 (No. 217-03101)	Apr-21
Reference 20 dB Attenuator	SN: CC2552 (20x)	31-Mar-20 (No. 217-03106)	Apr-21
DAE4	SN: 789	23-Dec-20 (No. DAE4-789 Dec20)	Dec-21
Reference Probe ER3DV6	SN: 2328	05-Oct-20 (No. ER3-2328_Oct20)	Oct-21
Secondary Standards	ID	Check Date (in house)	Scheduled Check
Power meter E4419B	SN: GB41293874	06-Apr-16 (in house check Jun-20)	In house check: Jun-22
Power sensor E4412A	SN: MY41498087	06-Apr-16 (in house check Jun-20)	In house check: Jun-22
Power sensor E4412A	SN: 000110210	06-Apr-16 (in house check Jun-20)	In house check: Jun-22
RF generator HP 8648C	SN: US3642U01700	04-Aug-99 (in house check Jun-20)	In house check: Jun-22
Network Analyzer E8358A	SN: US41080477	31-Mar-14 (in house check Oct-20)	In house check: Oct-21
	NI		
Calibrated by:	Name	Function	Signature
Calibrated by.	Michael Weber	Laboratory Technician	Millese
Approved by:	Katja Pokovic	Technical Manager	AUL
			Issued: February 16, 2021

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

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Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



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Multilateral Agreement for the recognition of calibration certificates Glossany:

Glossary.	
NORMx,y,z	sensitivity in free space
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C, D	modulation dependent linearization parameters
En	incident E-field orientation normal to probe axis
Ep	incident E-field orientation parallel to probe axis
Polarization φ	φ rotation around probe axis
Polarization &	$\vartheta$ rotation around an axis that is in the plane normal to probe axis (at measurement center),
	i.e., $\vartheta = 0$ is normal to probe axis
Connector Angle	information used in DASY system to align probe sensor X to the robot coordinate system

## Calibration is Performed According to the Following Standards:

- a) IEEE Std 1309-2005, " IEEE Standard for calibration of electromagnetic field sensors and probes, excluding
- antennas, from 9 kHz to 40 GHz", December 2005
- b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.1.1, May 2017

#### Methods Applied and Interpretation of Parameters:

- NORMx, y,z: Assessed for E-field polarization 9 = 0 for XY sensors and 9 = 90 for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z \* frequency\_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal • characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open ٠ waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

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EF3DV3 - SN:4035

February 15, 2021

## DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

## **Basic Calibration Parameters**

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm $(\mu V/(V/m)^2)$	0.90	0.73	1.19	± 10.1 %
DCP (mV) <sup>B</sup>	96.3	101.2	98.2	

## Calibration results for Frequency Response (30 MHz – 6 GHz)

Frequency	Target E-Field V/m	Measured E-field (En)	Deviation E-normal	Measured	Deviation	Unc (k=2)
MHz	•//11	V/m	in %	E-field (Ep) V/m	E-normal in %	%
30	77.1	77.0	-0.2%	77.2	0.1%	± 5.1 %
100	77.2	78.3	1.4%	77.8	0.7%	± 5.1 %
450	77.2	78.4	1.6%	77.9	1.0%	± 5.1 %
600	77.1	77.9	1.1%	77.4	0.5%	± 5.1 %
750	77.1	77.8	0.9%	77.3	0.3%	± 5.1 %
1800	143.1	139.0	-2.8%	139.4	-2.6%	± 5.1 %
2000	135.1	131.3	-2.7%	131.5	-2.6%	± 5.1 %
2200	127.7	123.4	-3.3%	124.5	-2.5%	± 5.1 %
2500	125.5	122.4	-2.5%	123.5	-1.6%	± 5.1 %
3000	79.4	75.6	-4.7%	76.7	-3.3%	± 5.1 %
3500	256.9	246.8	-3.9%	243.9	-4.8%	± 5.1 %
3700	251.2	240.8	-4.2%	237.9	-5.0%	± 5.1 %
5200	50.8	51.4	1.3%	51.7	1.9%	± 5.1 %
5500	47.0	46.8	-0.5%	48.2	2.7%	± 5.1 %
5800	48.8	48.6	-0.6%	47.1	-3.6%	± 5.1 %

## Calibration Results for Modulation Response

UID	Communication System Name		A dB	B dBõV	С	D dB	VR mV	Max dev.	Unc <sup>E</sup> (k=2)
0	CW	X	0.0	0.0	1.0	0.00	141.8	± 3.8 %	± 4.7 %
		Y	0.0	0.0	1.0		172.6		
		Z	0.0	0.0	1.0		171.7		

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

<sup>8</sup> Numerical linearization parameter: uncertainty not required.
<sup>6</sup> Uncertainty is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

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EF3DV3 - SN:4035

## DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

## **Sensor Frequency Model Parameters**

	Sensor X	Sensor Y	Sensor Z
Frequency Corr. (LF)	0.22	0.19	5.72
Frequency Corr. (HF)	2.82	2.82	2.82

### Other Probe Parameters

Sensor Arrangement	Rectangular
Connector Angle (°)	-126.8
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	12 mm
Tip Length	25 mm
Tip Diameter	4 mm
Probe Tip to Sensor X Calibration Point	1.5 mm
Probe Tip to Sensor Y Calibration Point	1.5 mm
Probe Tip to Sensor Z Calibration Point	1.5 mm

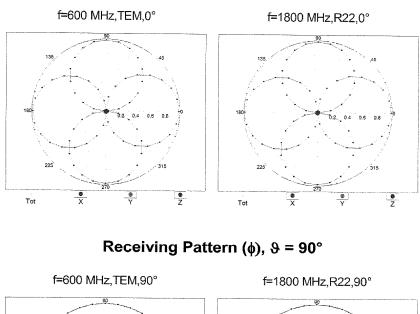
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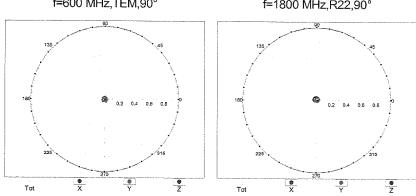
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Receiving Pattern ( $\phi$ ),  $\vartheta = 0^{\circ}$ 



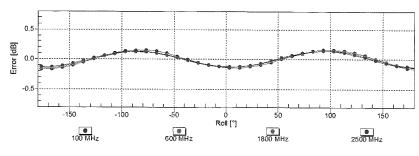
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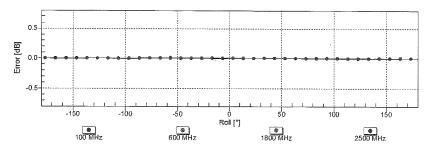
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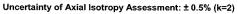


## Receiving Pattern ( $\phi$ ), $\vartheta = 0^{\circ}$

Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Receiving Pattern ( $\phi$ ),  $\vartheta = 90^{\circ}$ 



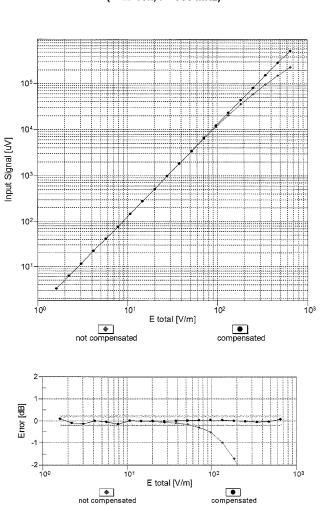


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## Dynamic Range f(E-field) (TEM cell, f = 900 MHz)

Uncertainty of Linearity Assessment: ± 0.6% (k=2)

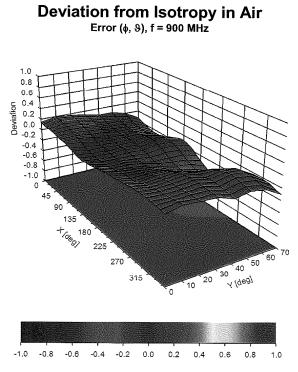
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EF3DV3 - SN:4035

## February 15, 2021



Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

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Swiss Calibration Service Accreditation No.: SCS 0108

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Client PC Test Certificate No: CD835V3-1003\_Jan21

Object	CD835V3 - SN: 1003				
Calibration procedure(s)	QA CAL-20.v7 Calibration Procedure for Validation Sources in air				
Calibration date:	January 14, 2021				
This calibration certificate documer	ts the traceability to nation	onal standards, which realize the physical uni	ts of measurements (SI).		
The measurements and the uncertain	ainties with confidence pr	obability are given on the following pages an	d are part of the certificate.		
All calibrations have been conducte	vt in the closed laborator	y facility: environment temperature (22 ± 3)*0	3/30/2		
		y laciny, environment temperature (22 ± 3) c	and numbery < 70%.		
Calibration Equipment used (M&TE					
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration		
Power meter NRP	SN: 104778	01-Apr-20 (No. 217-03100/03101)	Apr-21		
Power sensor NRP-Z91	SN: 103244	01-Apr-20 (No. 217-03100)	Apr-21		
Power sensor NRP-Z91	SN: 103245	01-Apr-20 (No. 217-03101)	Apr-21		
Reference 20 dB Attenuator	SN: BH9394 (20k)	31-Mar-20 (No. 217-03106)	Apr-21		
Type-N mismatch combination	SN: 310982 / 06327	31-Mar-20 (No. 217-03104)	Apr-21		
Probe EF3DV3	SN: 4013	28-Dec-20 (No. EF3-4013_Dec20)	Dec-21		
DAE4	SN: 781	23-Dec-20 (No. DAE4-781_Dec20)	Dec-21		
Secondary Standards	ID#	Check Date (in house)	Scheduled Check		
Power meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Oct-20)	In house check: Oct-23		
Power sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-20)	In house check: Oct-23		
Power sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-20)	In house check: Oct-23		
RF generator R&S SMT-06	SN: 837633/005	10-Jan-19 (in house check Oct-20)	In house check: Oct-23		
Network Analyzer Agilent E8358A	SN: US41080477	31-Mar-14 (in house check Oct-20)	In house check: Oct-21		
	Name	Function	Signature		
Calibrated by:	Leif Klysner	Laboratory Technician	Sef Elger		
Approved by:	Katja Pokovic	Technical Manager	ally		
			Issued: January 16, 2021		

Certificate No: CD835V3-1003\_Jan21

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#### References

#### [1] ANSI-C63.19-2011

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic E-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any nonparallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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## **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.4
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	835 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

## Maximum Field values at 835 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	109.9 V/m = 40.82 dBV/m	
Maximum measured above low end	100 mW input power	106.8 V/m = 40.57 dBV/m	
Averaged maximum above arm	100 mW input power	108.4 V/m ± 12.8 % (k=2)	

## Appendix (Additional assessments outside the scope of SCS 0108)

### **Antenna Parameters**

Frequency	Return Loss	Impedance	
800 MHz	17.0 dB	40.3 Ω - 8.2 jΩ	
835 MHz	24.5 dB	52.9 Ω + 5.4 jΩ	
880 MHz	17.2 dB	61.3 Ω - 10.6 jΩ	
900 MHz	18.6 dB	50.5 Ω - 11.9 jΩ	
945 MHz	21.9 dB	51.3 Ω + 8.0 jΩ	

### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

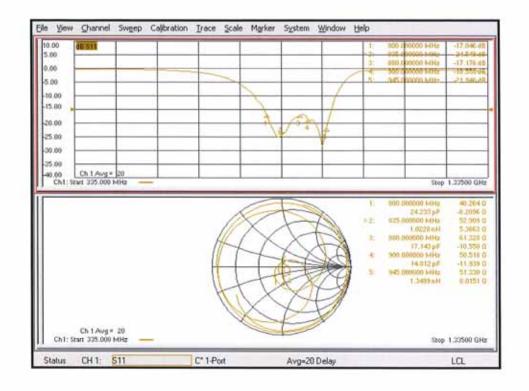
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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## Impedance Measurement Plot



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## **DASY5 E-field Result**

Date: 14.01.2021

Test Laboratory: SPEAG Lab2

## DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1003

Communication System: UID 0 - CW ; Frequency: 835 MHz Medium parameters used:  $\sigma = 0$  S/m,  $\epsilon_r = 1$ ;  $\rho = 0$  kg/m<sup>3</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

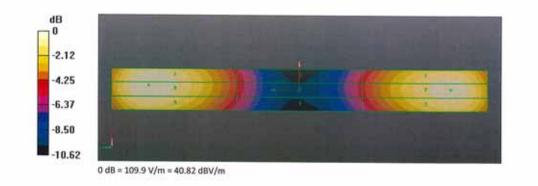
- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 835 MHz; Calibrated: 28.12.2020
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 23.12.2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.4(1527); SEMCAD X 14.6.14(7483)

Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=15mm/Hearing Aid Compatibility Test (41x361x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 132.2 V/m; Power Drift = 0.03 dB Applied MIF = 0.00 dB

RF audio interference level = 40.82 dBV/m Emission category: M3

MIF scaled E-field

Grid 1 M3	Grid 2 M3	Grid 3 M3
40.45 dBV/m	40.57 dBV/m	40.35 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
35.95 dBV/m	35.96 dBV/m	35.61 dBV/m
	Grid 8 M3 40.82 dBV/m	Grid 9 M3 40.4 dBV/m



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Client PC Test Certificate No: CD1880V3-1137\_Jan21 CALIBRATION CERTIFICATE CD1880V3 - SN: 1137 Object Calibration procedure(s) QA CAL-20.v7 Calibration Procedure for Validation Sources in air January 14, 2021 Calibration date: This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)\*C and humidity < 70%. 3/30/2021 Calibration Equipment used (M&TE critical for calibration) Primary Standards ID# Cal Date (Certificate No.) Scheduled Calibration Power meter NRP SN: 104778 01-Apr-20 (No. 217-03100/03101) Apr-21 Power sensor NRP-Z91 SN: 103244 01-Apr-20 (No. 217-03100) Apr-21 Power sensor NRP-Z91 SN: 103245 01-Apr-20 (No. 217-03101) Apr-21 Reference 20 dB Attenuator SN: BH9394 (20k) 31-Mar-20 (No. 217-03106) Apr-21 Type-N mismatch combination SN: 310982 / 06327 31-Mar-20 (No. 217-03104) Apr-21 Probe EF3DV3 SN: 4013 28-Dec-20 (No. EF3-4013\_Dec20) Dec-21 DAE4 SN: 781 23-Dec-20 (No. DAE4-781\_Dec20) Dec-21 Secondary Standards ID # Check Date (in house) Scheduled Check Power meter Agilent 4419B SN: GB42420191 09-Oct-09 (in house check Oct-20) In house check: Oct-23 Power sensor HP E4412A SN: US38485102 05-Jan-10 (in house check Oct-20) In house check: Oct-23 SN: US37295597 Power sensor HP 8482A 09-Oct-09 (in house check Oct-20) In house check: Oct-23 RF generator R&S SMT-06 SN: 837633/005 10-Jan-19 (in house check Oct-20) In house check: Oct-23 Network Analyzer Agilent E8358A SN: US41080477 31-Mar-14 (in house check Oct-20) In house check: Oct-21 Name Function Signature Calibrated by: Loif Klysner Laboratory Technician Approved by: Katia Pokovic Technical Manager Issued: January 16, 2021 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

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#### References

- [1] ANSI-C63.19-2011
  - American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
  figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
  is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
  directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic E-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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#### **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.4
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	1730 MHz ± 1 MHz 1880 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

# Maximum Field values at 1730 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	94.2 V/m = 39.48 dBV/m
Maximum measured above low end	100 mW input power	93.8 V/m = 39.44 dBV/m
Averaged maximum above arm	100 mW input power	94.0 V/m ± 12.8 % (k=2)

## Maximum Field values at 1880 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	88.0 V/m = 38.89 dBV/m
Maximum measured above low end	100 mW input power	87.8 V/m = 38.87 dBV/m
Averaged maximum above arm	100 mW input power	87.9 V/m ± 12.8 % (k=2)

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# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

#### **Nominal Frequencies**

Frequency	Return Loss	Impedance
1730 MHz	22.8 dB	54.0 Ω + 6.4 jΩ
1880 MHz	21.4 dB	56.8 Ω + 6.0 jΩ
1900 MHz	22.7 dB	57.2 Ω + 3.0 jΩ
1950 MHz	27.9 dB	52.3 Ω - 3.4 jΩ
2000 MHz	20.4 dB	42.8 Ω + 5.2 jΩ

#### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth. The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is

therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

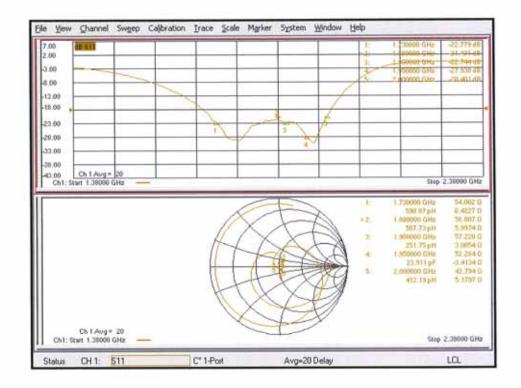
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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# Impedance Measurement Plot



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#### **DASY5 E-field Result**

Date: 14.01.2021

Test Laboratory: SPEAG Lab2

#### DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1137

Communication System: UID 0 - CW ; Frequency: 1880 MHz, Frequency: 1730 MHz Medium parameters used:  $\sigma = 0$  S/m,  $z_e = 1$ ;  $\rho = 0$  kg/m<sup>3</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 1880 MHz, ConvF(1, 1, 1) @ 1730 MHz; Calibrated: 28.12.2020
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 23.12.2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.4(1527); SEMCAD X 14.6.14(7483)

Dipole E-Field measurement @ 1880MHz/E-Scan - 1880MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm Reference Value = 157.0 V/m; Power Drift = 0.02 dB Applied MIF = 0.00 dB RF audio interference level = 38.89 dBV/m Emission category: M2

**MIF** scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
38.7 dBV/m	38.87 dBV/m	38.68 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
36.04 dBV/m	36.09 dBV/m	35.98 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 MZ
38.81 dBV/m	38.89 dBV/m	38.56 dBV/m

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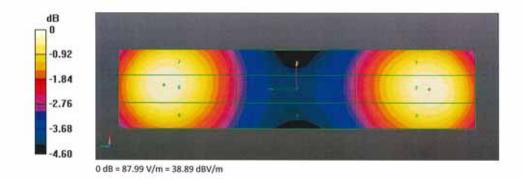
FCC ID: A3LSMS906U	PCTEST	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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#### Dipole E-Field measurement @ 1880MHz/E-Scan - 1730MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm

Reference Value = 169.8 V/m; Power Drift = 0.01 dB Applied MIF = 0.00 dB RF audio interference level = 39.48 dBV/m Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
39.27 dBV/m	39.44 dBV/m	39.24 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
36.67 dBV/m	36.74 dBV/m	36.58 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
39.39 dBV/m	39.48 dBV/m	39.13 dBV/m



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Certificate No: CD2600V3-1012\_Jan21

Object	CD2600V3 - SN: 1012		
Calibration procedure(s)	QA CAL-20.v7 Calibration Proce	r	
Calibration date:	January 14, 2021		
This calibration certificate documen	its the traceability to natio	onal standards, which realize the physical un	its of measurements (SI).
The measurements and the uncerta	ainties with confidence pr	obability are given on the following pages ar	d are part of the certificate.
All calibrations have been conducted	d in the closed laboratory	y facility: environment temperature (22 ± 3)*	
vi calibrations have been conducte	ad in the closed laborator	y tability: environment temperature (22 ± 3)	and numberly < 70%.
Calibration Equipment used (M&TE	critical for calibration)		11 24/24
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	01-Apr-20 (No. 217-03100/03101)	Apr-21
Power sensor NRP-Z91	SN: 103244	01-Apr-20 (No. 217-03100)	Apr-21
Power sensor NRP-Z91	SN: 103245	01-Apr-20 (No. 217-03101)	Apr-21
Reference 20 dB Attenuator	SN: BH9394 (20k)	31-Mar-20 (No. 217-03106)	Apr-21
Type-N mismatch combination	SN: 310982 / 06327	31-Mar-20 (No. 217-03104)	Apr-21
Probe EF3DV3	SN: 4013	28-Dec-20 (No. EF3-4013_Dec20)	Dec-21
DAE4	SN: 781	23-Dec-20 (No. DAE4-781_Dec20)	Dec-21
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Power meter Agilent 44198	SN: G842420191	09-Oct-09 (in house check Oct-20)	In house check: Oct-23
Power sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-20)	In house check: Oct-23
Power sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-20)	In house check: Oct-23
RF generator R&S SMT-06	SN: 837633/005	10-Jan-19 (in house check Oct-20)	In house check: Oct-23
Network Analyzer Agilent E8358A	SN: US41080477	31-Mar-14 (in house check Oct-20)	In house check: Oct-21
	Name	Function	Signature
Calibrated by:	Leif Klysner	Laboratory Technician	Sed Eller
Approved by:	Katja Pokovic	Technical Manager	
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#### References

[1] ANSI-C63.19-2011

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
  figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
  is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
  directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic E-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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6/22/2020

#### **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.4
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	2600 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

#### Maximum Field values at 2600 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	86.8 V/m = 38.77 dBV/m
Maximum measured above low end	100 mW input power	86.3 V/m = 38.72 dBV/m
Averaged maximum above arm	100 mW input power	86.5 V/m ± 12.8 % (k=2)

#### Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

Frequency	Return Loss	Impedance
2450 MHz	20.9 dB	43.7 Ω - 5.7 jΩ
2550 MHz	32.2 dB	48.5 Ω + 1.9 jΩ
2600 MHz	35.0 dB	51.4 Ω + 1.1 jΩ
2650 MHz	31.6 dB	52.4 Ω - 1.2 jΩ
2750 MHz	22.3 dB	48.4 Ω - 7.4 jΩ

#### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

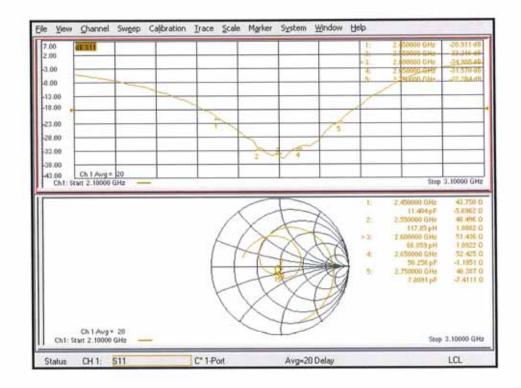
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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### Impedance Measurement Plot



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#### **DASY5 E-field Result**

Date: 14.01.2021

Test Laboratory: SPEAG Lab2

# DUT: HAC Dipole 2600 MHz; Type: CD2600V3; Serial: CD2600V3 - SN: 1012

Communication System: UID 0 - CW ; Frequency: 2600 MHz Medium parameters used:  $\sigma = 0$  S/m,  $\epsilon_r = 1$ ;  $\rho = 0$  kg/m<sup>3</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

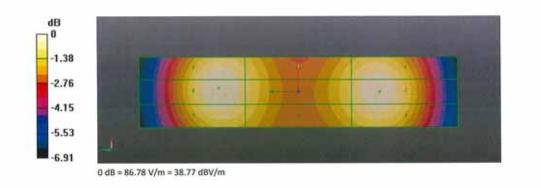
- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 2600 MHz; Calibrated: 28.12.2020
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 23.12.2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.4(1527); SEMCAD X 14.6.14(7483)

Dipole E-Field measurement @ 2600MHz/E-Scan - 2600MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 67.09 V/m; Power Drift = -0.03 dB

Applied MIF = 0.00 dB RF audio interference level = 38.77 dBV/m Emission category: M2

MIF scaled E-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
38.56 dBV/m	38.72 dBV/m	38.5 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
38.08 dBV/m	38.12 dBV/m	37.92 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
38.69 dBV/m	38.77 dBV/m	38.5 dBV/m



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Client PC Test

Certificate No: CD3500V3-1005\_Oct20

Object	CD3500V3 - SN:	1005	
Calibration procedure(s)	QA CAL-20.v7 Calibration Proce	dure for Validation Sources in ai	r
Calibration date:	October 20, 2020		
The measurements and the uncert	ainties with confidence p	onal standards, which realize the physical un obability are given on the following pages an y facility: environment temperature (22 ± 3)*0	d are part of the certificate.
Calibration Equipment used (M&TE Primary Standards	critical for calibration)	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	01-Apr-20 (No. 217-03100/03101)	Apr-21
Power sensor NRP-Z91	SN: 103244	01-Apr-20 (No. 217-0310003101)	Apr-21
Power sensor NRP-291	SN: 103245	01-Apr-20 (No. 217-03101)	Apr-21
Reference 20 dB Attenuator	SN: BH9394 (20k)	31-Mar-20 (No. 217-03106)	Apr-21
Type-N mismatch combination	SN: 310982 / 06327	31-Mar-20 (No. 217-03104)	Apr-21
Probe EF3DV3	SN: 4013	31-Dec-19 (No. EF3-4013 Dec19)	Dec-20
DAE4	SN: 781	27-Dec-19 (No. DAE4-781_Dec19)	Dec-20
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Power meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Oct-20)	In house check: Oct-23
Power sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-20)	In house check: Oct-23
Power sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-20)	In house check: Oct-23
RF generator R&S SMT-06	SN: 837633/005	10-Jan-19 (in house check Oct-20)	In house check: Oct-23
Network Analyzer Agilent E8358A	SN: US41080477	31-Mar-14 (in house check Oct-20)	In house check: Oct-21
	Name	Function	Signature
Calibrated by:	Leif Riysner	Laboratory Technician	Sel Illen
Approved by:	Katja Pokovic	Technical Manager	lack

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Accreditation No.: SCS 0108

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#### References

#### ANSI-C63 19-2011 [1]

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

# Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic E-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any nonparallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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#### **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.4
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	3500 MHz ± 1 MHz 3900 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

# Maximum Field values at 3500 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	85.3 V/m = 38.61 dBV/m
Maximum measured above low end	100 mW input power	83.6 V/m = 38.44 dBV/m
Averaged maximum above arm	100 mW input power	84.4 V/m ± 12.8 % (k=2)

# Maximum Field values at 3900 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	82.0 V/m = 38.28 dBV/m	
Maximum measured above low end	100 mW input power	79.9 V/m = 38.05 dBV/m	
Averaged maximum above arm	100 mW input power	81.0 V/m ± 12.8 % (k=2)	

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## Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

#### **Nominal Frequencies**

Frequency	Return Loss	Impedance
3300 MHz	22.3 dB	58.2 Ω + 0.9 jΩ
3400 MHz	31.4 dB	52.7 Ω - 0.2 jΩ
3500 MHz	25.0 dB	55.4 Ω - 2.4 ]Ω
3600 MHz	21.1 dB	49.4 Ω - 8.8 jΩ
3700 MHz	19.6 dB	41.0 Ω - 3.2 jΩ

#### **Additional Frequencies**

Frequency	Return Loss	Impedance
3900 MHz	17.0 dB	47.7 Ω + 13.8 jΩ

#### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

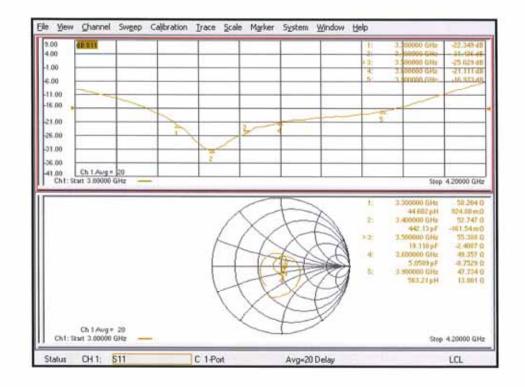
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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#### Impedance Measurement Plot



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#### **DASY5 E-field Result**

Date: 20.10.2020

Test Laboratory: SPEAG Lab2

# DUT: HAC Dipole 3500 MHz; Type: CD3500V3; Serial: CD3500V3 - SN: 1005

Communication System: UID 0 - CW ; Frequency: 3500 MHz, Frequency: 3900 MHz Medium parameters used:  $\sigma = 0$  S/m,  $\epsilon_r = 1$ ;  $\rho = 0$  kg/m<sup>3</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 3500 MHz, ConvF(1, 1, 1) @ 3900 MHz; Calibrated: 31.12.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 27.12.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.4(1527); SEMCAD X 14.6.14(7483)

Dipole E-Field measurement @ 3500MHz/E-Scan - 3500MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm

Reference Value = 34.56 V/m; Power Drift = 0.03 dB Applied MIF = 0.00 dB RF audio interference level = 38.61 dBV/m

Emission category: M2

#### MIF scaled E-field

	Grid 2 M2 38.44 dBV/m	Grid 3 M2 38.36 dBV/m
Grid 4 M2 38.41 dBV/m	Grid 5 M2 38.61 dBV/m	Grid 6 M2 38.5 dBV/m
Grid 7 M2 38.41 dBV/m		Grid 9 M2 38.49 dBV/m

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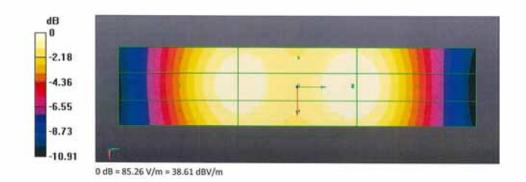
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Dipole E-Field measurement @ 3500MHz/E-Scan - 3900MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 31.52 V/m; Power Drift = -0.01 dB

Applied MIF = 0.00 dB

RF audio interference level = 38.28 dBV/m Emission category: M2

	Grid 2 M2 38.05 dBV/m	Grid 3 M2 37.98 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
38.11 dBV/m	38.28 dBV/m	38.16 dBV/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
38.09 d8V/m	38.25 dBV/m	38.13 dBV/m



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Swiss Calibration Service

Accreditation No.: SCS 0108

Client PC Test Certificate No: CD3500V3-1015 Mar21 CALIBRATION CERTIFICATE CD3500V3 - SN: 1015 Object QA CAL-20 v7 Calibration procedure(s) Calibration Procedure for Validation Sources in air Calibration date: March 02, 2021 This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI), The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)\*C and humidity < 70%. 3/30/202 Calibration Equipment used (M&TE critical for calibration) ID# Primary Standards Cal Date (Certificate No.) Scheduled Calibration Power meter NRP SN: 104778 01-Apr-20 (No. 217-03100/03101) Apr-21 Power sensor NRP-Z91 SN: 103244 01-Apr-20 (No. 217-03100) Apr-21 Power sensor NRP-Z91 SN: 103245 01-Apr-20 (No. 217-03101) Apr-21 Reference 20 dB Attenuator SN: BH9394 (20k) 31-Mar-20 (No. 217-03106) Apr-21 SN: 310982 / 06327 Type-N mismatch combination 31-Mar-20 (No. 217-03104) Apr-21 Probe EF3DV3 SN: 4013 28-Dec-20 (No. EF3-4013\_Dec20) Dec-21 DAE4 SN: 781 23-Dec-20 (No. DAE4-781\_Dec20) Dec-21 Secondary Standards ID# Check Date (in house) Scheduled Check Power meter Agilent 4419B SN: GB42420191 09-Oct-09 (in house check Oct-20) In house check: Oct-23 Power sensor HP E4412A SN: US38485102 05-Jan-10 (in house check Oct-20) In house check: Oct-23 Power sensor HP 8482A SN: US37295597 09-Oct-09 (in house check Oct-20) In house check: Oct-23 RF generator R&S SMT-06 SN: 837633/005 10-Jan-19 (in house check Oct-20) In house check: Oct-23 Network Analyzer Agilent E8358A SN: US41080477 31-Mar-14 (in house check Oct-20) In house check: Oct-21 Name Function Signature Leif Klysner Calibrated by: Laboratory Technician Approved by: Katja Pokovic Technical Manager Issued: March 2, 2021 This calibration certificate shall not be reproduced except in full without written approval of the laboratory

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#### References

ANSI-C63.19-2011 [1]

American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic E-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any nonparallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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# **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.4
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	3500 MHz ± 1 MHz 3900 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

## Maximum Field values at 3500 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	83.1 V/m = 38.39 dBV/m	
Maximum measured above low end	100 mW input power	82.5 V/m = 38.33 dBV/m	
Averaged maximum above arm	100 mW input power	82.8 V/m ± 12.8 % (k=2)	

# Maximum Field values at 3900 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	81.3 V/m = 38.21 dBV/m
Maximum measured above low end	100 mW input power	80.4 V/m = 38.11 dBV/m
Averaged maximum above arm	100 mW input power	80.9 V/m ± 12.8 % (k=2)

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# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

**Nominal Frequencies** 

Frequency	Return Loss	Impedance
3300 MHz	18.2 dB	64.0 Ω + 0.0 jΩ
3400 MHz	23.0 dB	54.3 Ω - 6.0 jΩ
3500 MHz	24.2 dB	50.0 Ω - 6.2 jΩ
3600 MHz	21.9 dB	44.8 Ω - 5.5 jΩ
3700 MHz	21.1 dB	42.1 Ω + 1.5 jΩ

#### **Additional Frequencies**

Frequency	Return Loss	Impedance
3900 MHz	20.3 dB	51.2 Ω + 9.7 jΩ

#### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

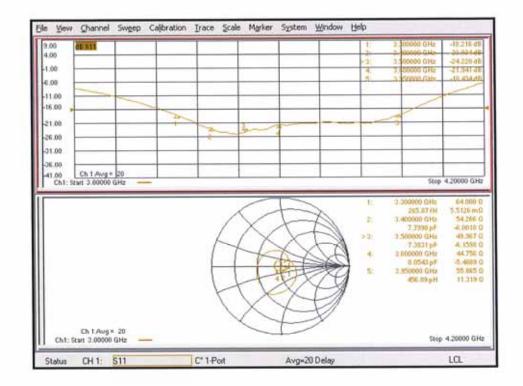
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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# Impedance Measurement Plot



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#### **DASY5 E-field Result**

Date: 02.03.2021

Test Laboratory: SPEAG Lab2

# DUT: HAC Dipole 3500 MHz; Type: CD3500V3; Serial: CD3500V3 - SN: 1015

 $\begin{array}{l} \mbox{Communication System: UID 0 - CW ; Frequency: 3500 MHz, Frequency: 3900 MHz} \\ \mbox{Medium parameters used: } \sigma = 0 \ S/m, \ \epsilon_r = 1; \ \rho = 0 \ kg/m^3 \\ \mbox{Phantom section: RF Section} \\ \mbox{Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)} \\ \end{array}$ 

**DASY52** Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 3500 MHz, ConvF(1, 1, 1) @ 3900 MHz; Calibrated: 28.12.2020
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 23.12.2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.4(1527); SEMCAD X 14.6.14(7483)

Dipole E-Field measurement @ 3500MHz/E-Scan - 3500MHz d=15mm/Hearing Aid Compatibility Test (41x121x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm

MIE scaled E-field

Device Reference Point: 0, 0, -6.3 mm Reference Value = 36.09 V/m; Power Drift = 0.01 dB Applied MIF = 0.00 dB RF audio interference level = 38.39 dBV/m Emission category: M2

Grid 1 M2 38.27 dBV/m	C 1 2 2 1 7 2 2 3 7 1	Grid 3 M2 38.18 dBV/m
Grid 4 M2		Grid 6 M2
	E. S.	Grid 9 M2 38.13 dBV/m

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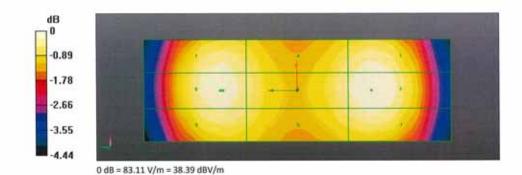
Dipole E-Field measurement @ 3900MHz/E-Scan - 3900MHz d=15mm/Hearing Aid Compatibility Test (41x121x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 32.96 V/m; Power Drift = -0.00 dB Applied MIF = 0.00 dB

contraction of the

RF audio interference level = 38.21 dBV/m

Emission category: M2

MIF scaled E-fi	eld	
	Grid 2 M2 38.21 dBV/m	Grid 3 M2 38.03 dBV/m
	Grid 5 M2 37.96 d8V/m	Grid 6 M2 37.84 dBV/m
Grid 7 M2 38 dBV/m	0.0000000000000000000000000000000000000	Grid 9 M2 37.92 dBV/m



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# 16. CONCLUSION

The measurements indicate that the referenced wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

Please note that the M-rating for this equipment only represents the field interference possible against a hypothetical and typical hearing aid. The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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